

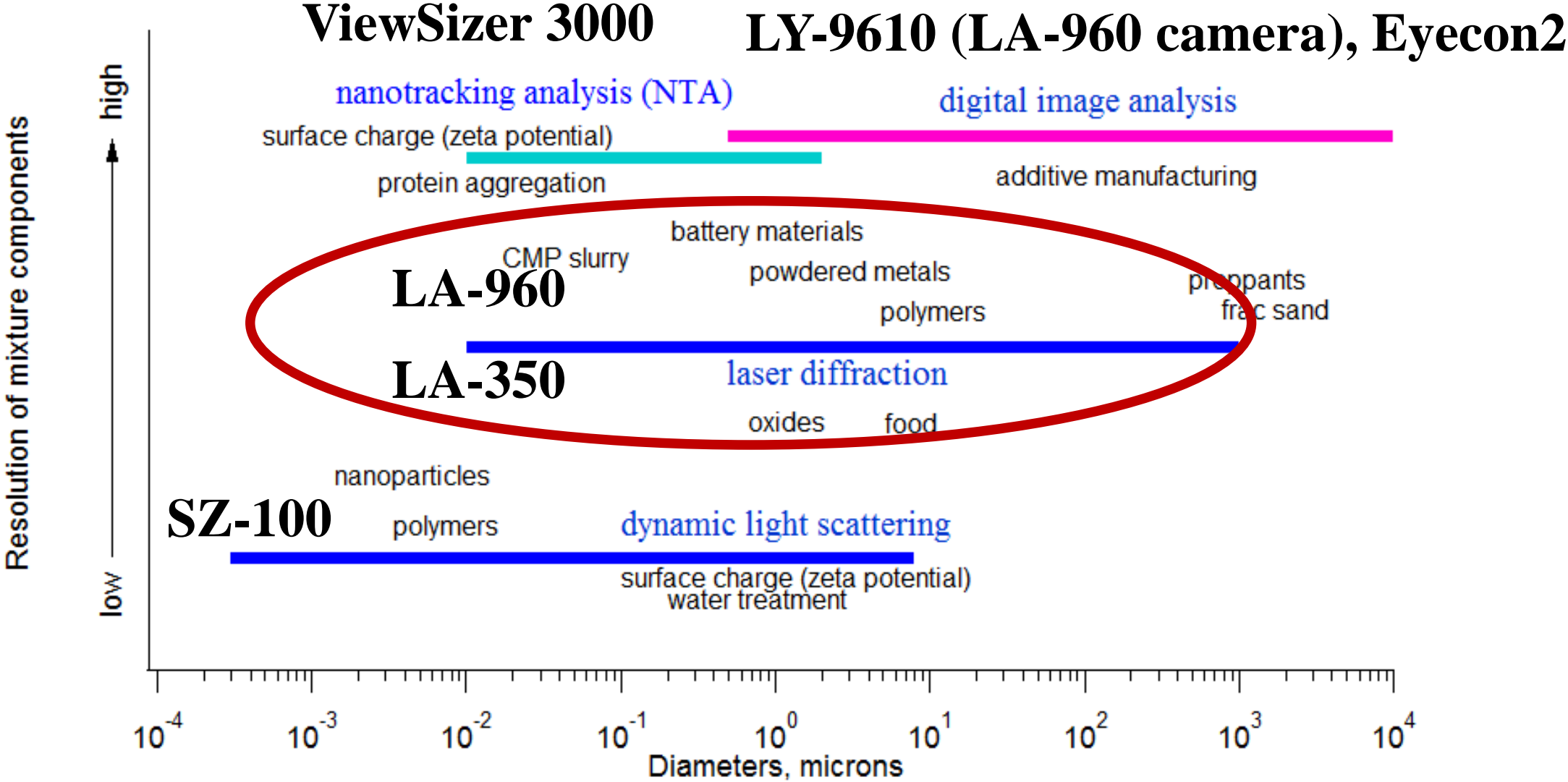
**HORIBA Scientific**  
**Particle Characterization**

# **Introduction to Laser Diffraction**

**Jeffrey Bodycomb, Ph.D.**

February 24, 2022

# Perspective



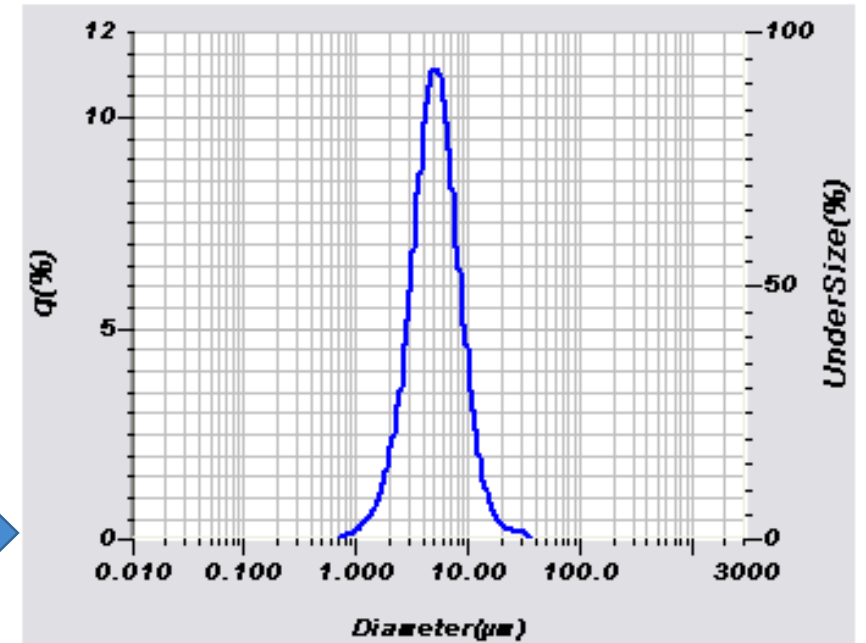
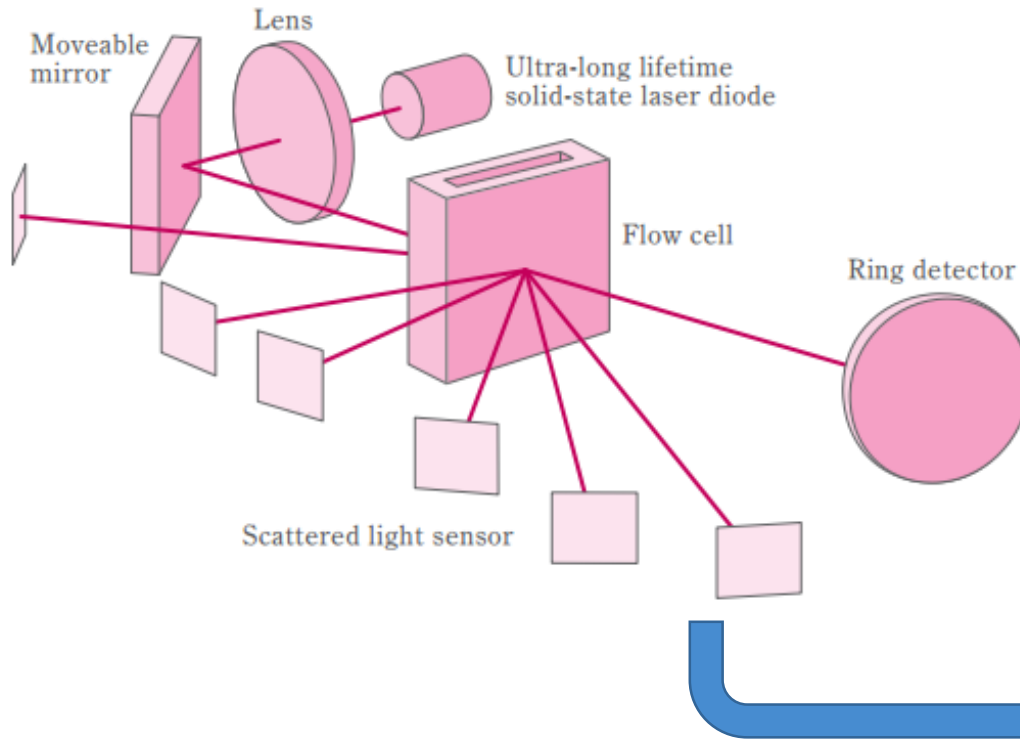
# Why Particle Size?

Size affects material behavior and processing across a number of industries.

| Industry    |  | Industry       |   |
|-------------|--|----------------|---|
| Ceramic     |    | Construction   |    |
| Oil/rubber  |    | Chemical       |    |
| Battery     |    | Pharmaceutical |    |
| Electricity |   | Food/Drink     |   |
| Automobile  |  | Paper/Pulp     |  |
| Mining      |  | Ink/Toner      |  |

# Core Principle

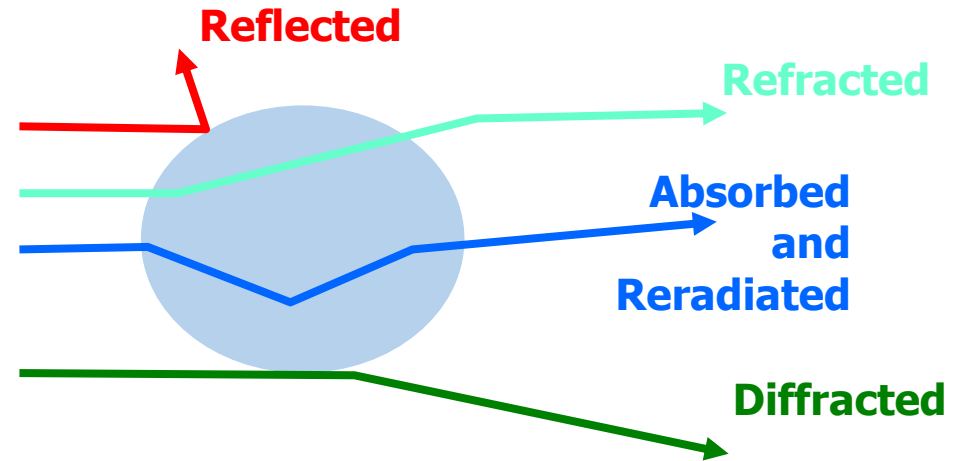
Investigate a particle sample with light and determine size distribution.



# When light strikes a particle

## Some of the light is:

- Diffacted
- Reflected
- Refracted
- Absorbed and Reradiated



**Small particles require knowledge of optical properties to tell math what light does inside of particle:**

Real Refractive Index (bending of light, wavelength of light in particle)

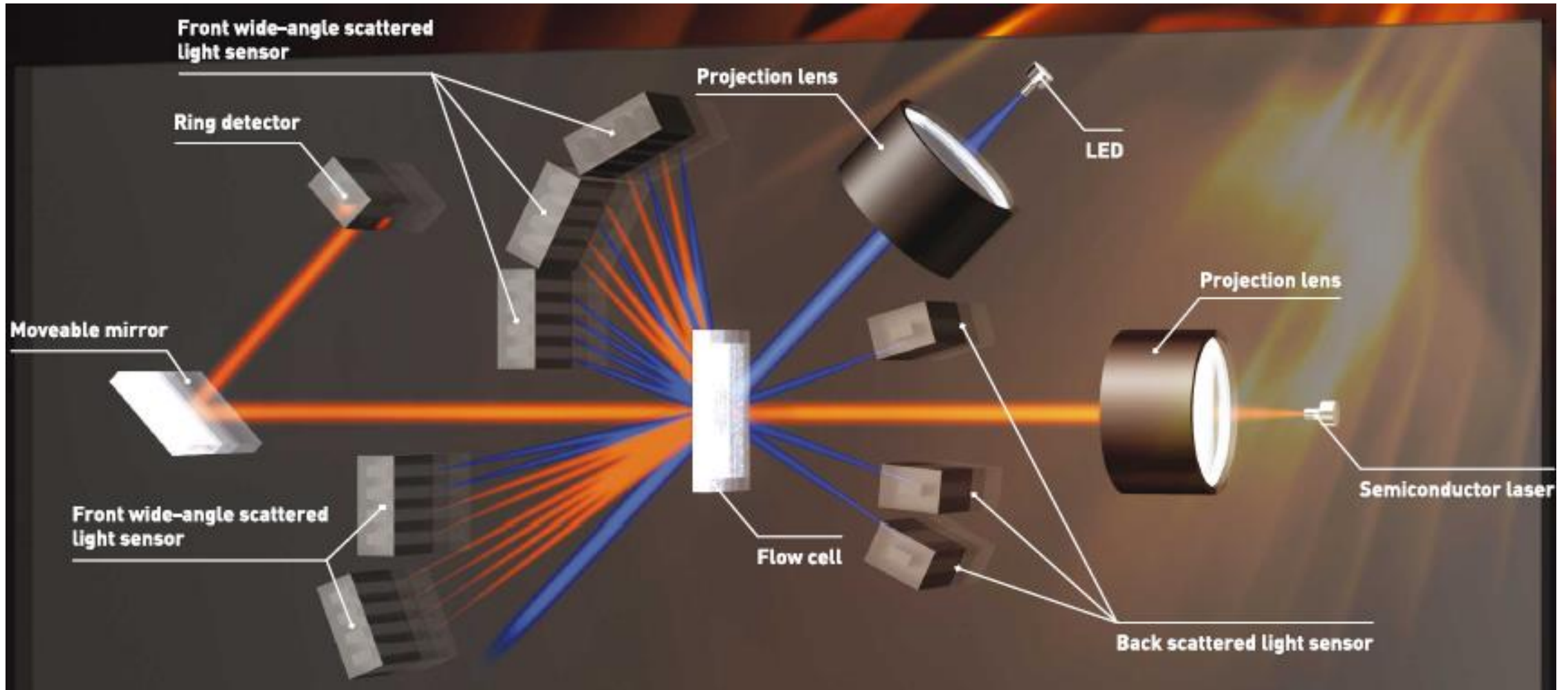
Imaginary Refractive Index (absorption of light within particle)

Refractive index values less significant for large particles

**Light must be collected over large range of angles**

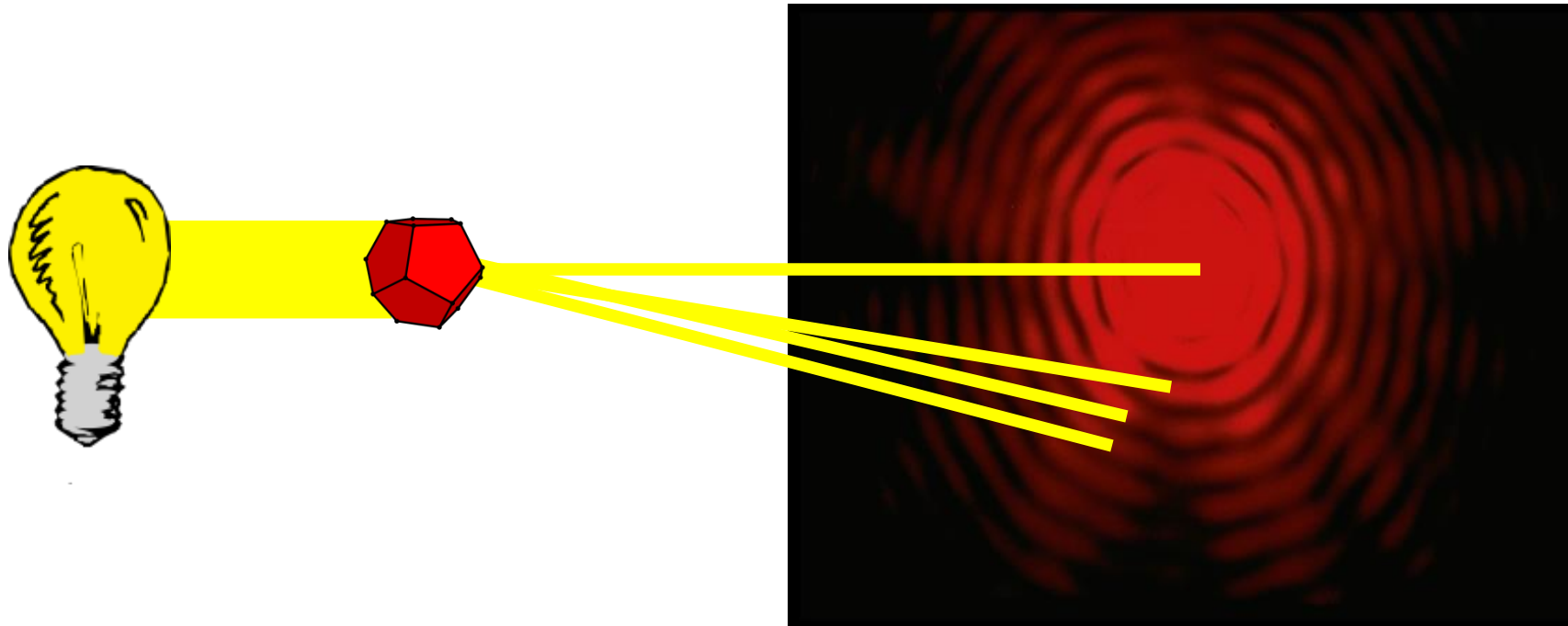


# LA-960 optics



# Diffraction pattern

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# Light

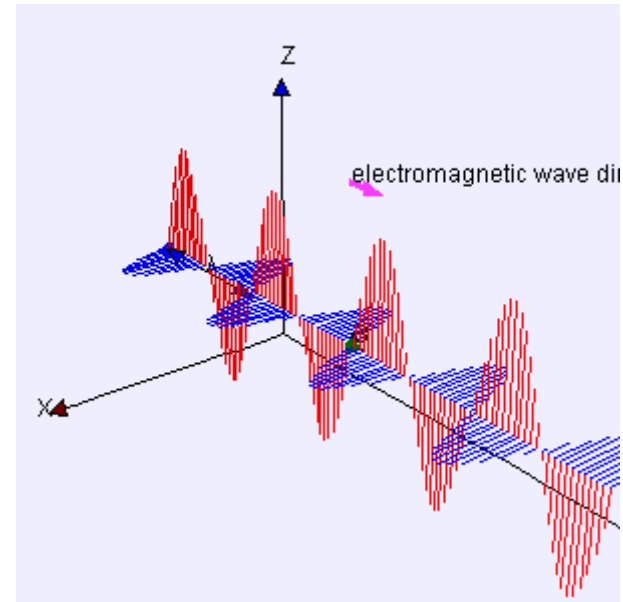
Expressed in just in y-direction

$$E = E_0 \sin(ky - \omega t)$$

$$H = H_0 \sin(ky - \omega t)$$

Oscillating electric field

Oscillating magnetic field (orthogonal to electric field)



Complements of Lookang @ [weelookang.blogspot.com](http://weelookang.blogspot.com)



# Light: Interference

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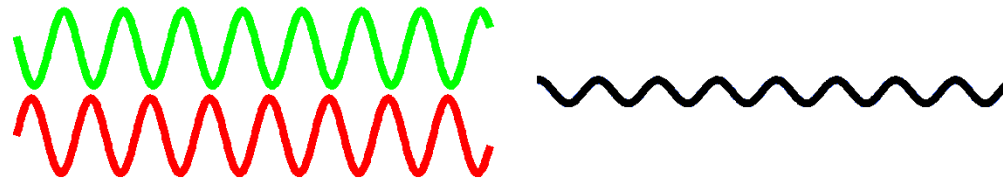
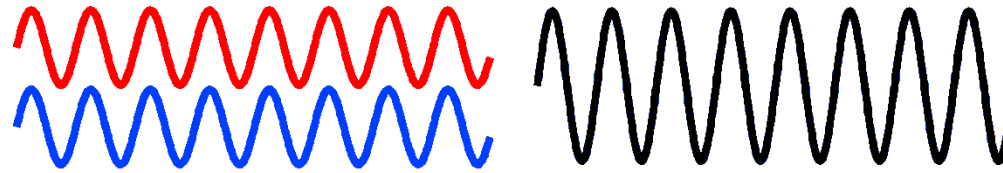
Look at just the electric field.

$$E = E_0 \sin(kx - \omega t + \phi)$$

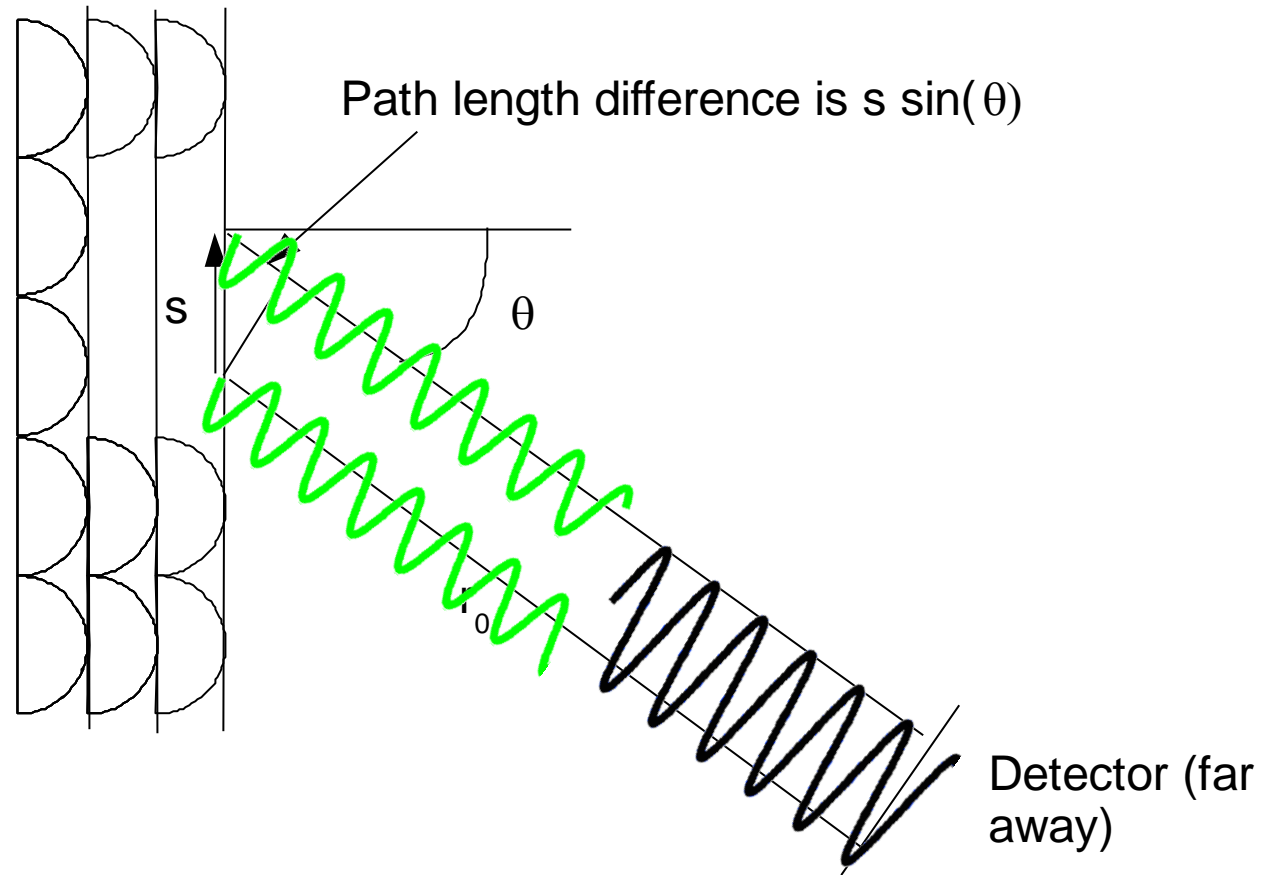
$$E = E_0 \sin(kx - \omega t)$$

Oscillating electric field

Second electric field with phase shift



# Path Length Difference



# Use models to interpret data

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**Scattering data typically cannot be inverted to find particle shape.**

**We use optical models to interpret data and understand our experiments.**

# Laser Diffraction Models

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## Large particles -> Fraunhofer

More straightforward math

Large, opaque particles as 2-D disks

Use this to develop intuition

## All particle sizes -> Mie

Messy calculations

All particle sizes as 3-D spheres

# Fraunhofer Approximation

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$$(S_1)^2 = (S_2)^2 = \alpha^4 \left[ \frac{J_1(\alpha \sin \Theta)}{\alpha \sin \Theta} \right]^2$$
$$I(\Theta) = \frac{I_0}{k^2 a^2} \alpha^4 \left[ \frac{J_1(\alpha \sin \Theta)}{\alpha \sin \Theta} \right]^2$$

dimensionless size parameter  $\alpha = \pi D/\lambda$ ;

$J_1$  is the Bessel function of the first kind of order unity.

Assumptions:

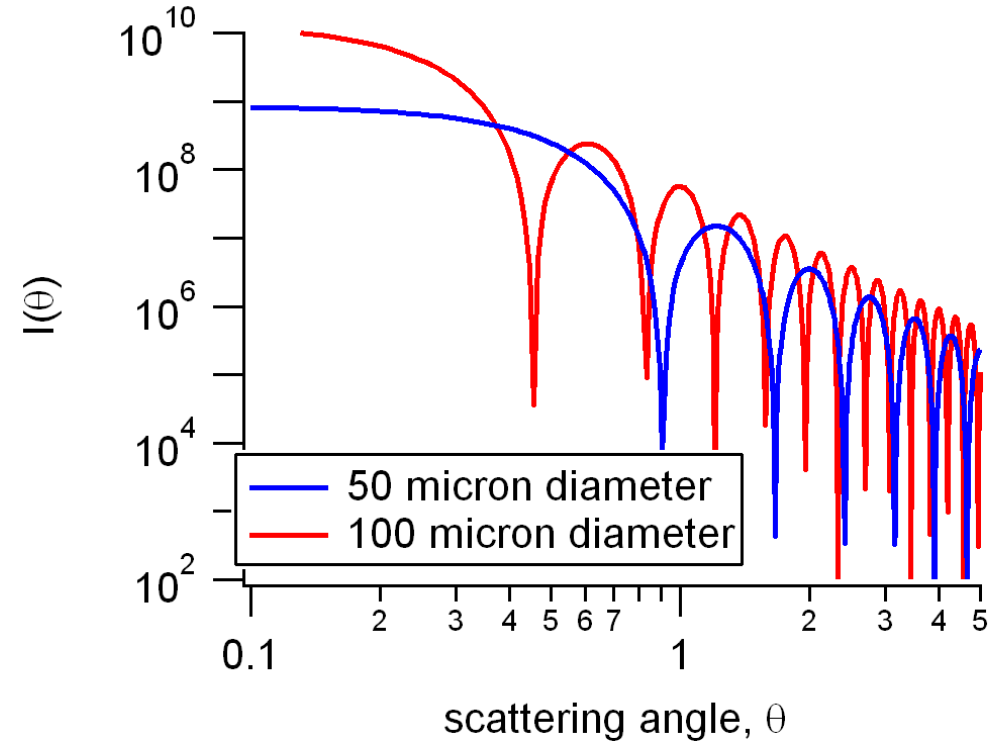
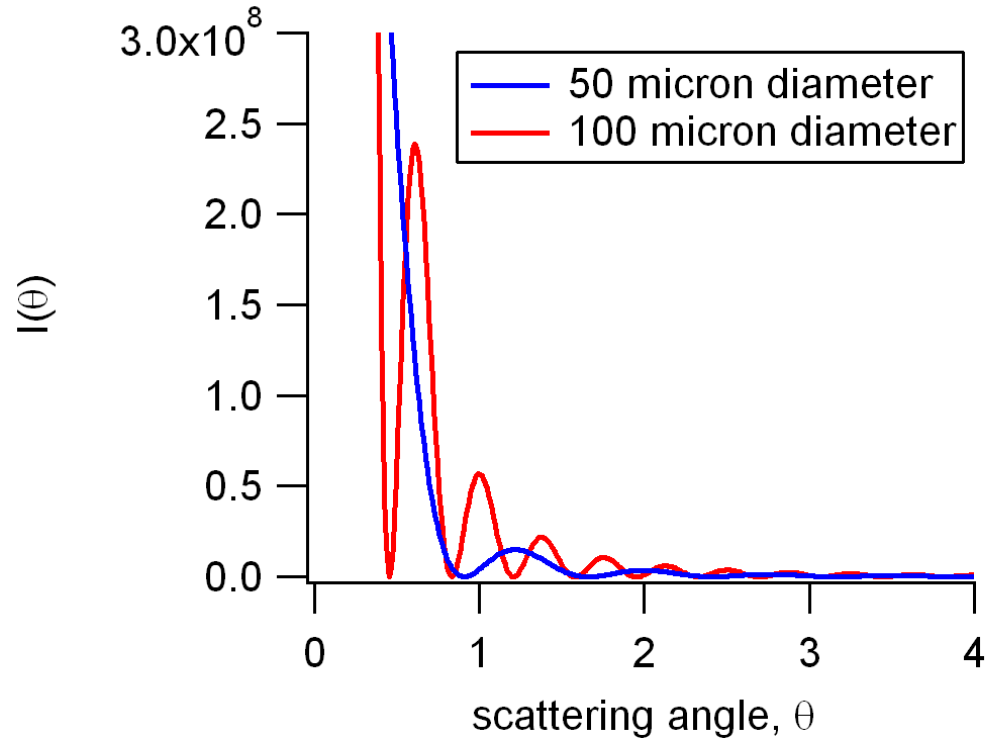
- a) all particles are much larger than the light wavelength (only scattering at the contour of the particle is considered; this also means that the same scattering pattern is obtained as for thin two-dimensional circular disks)
- b) only scattering in the near-forward direction is considered ( $Q$  is small).

Limitation: (diameter at least about 40 times the wavelength of the light, or  $\alpha \gg 1$ )\*

If  $\lambda=650\text{nm}$  ( $.65 \mu\text{m}$ ), then  $40 \times .65 = 26 \mu\text{m}$

If the particle size is larger than about **50  $\mu\text{m}$** , then the Fraunhofer approximation gives good results.

# Fraunhofer: Effect of Particle Size



**Smaller angles for larger particles**  
**High intensity for larger particles**

# Poll

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**Do you work with Particles**

**Over 1 mm?**

**Between 50 microns and 1 mm?**

**Between 2 microns and 50 microns?**

**Less than 2 microns?**



# Mie Scattering

$$I_s(m, x, \theta) = \frac{I_0}{2k^2 r^2} \left( |S_2|^2 + |S_1|^2 \right)$$

Use computer for the calculations!

$$S_1(m, x, \theta) = \sum_1^{\infty} \frac{2n+1}{n(n+1)} \{a_n \pi_n + b_n \tau_n\}$$

$$S_2(m, x, \theta) = \sum_1^{\infty} \frac{2n+1}{n(n+1)} \{a_n \tau_n + b_n \pi_n\}$$

$$a_n = \frac{m \psi_n(mx) \psi_n'(x) - \psi_n(x) \psi_n'(mx)}{m \psi_n(mx) \xi_n'(x) - \xi_n(x) \psi_n'(mx)}$$

$$b_n = \frac{\psi_n(mx) \psi_n'(x) - m \psi_n(x) \psi_n'(mx)}{\psi_n(mx) \xi_n'(x) - m \xi_n(x) \psi_n'(mx)}$$

$$\pi_n = \frac{P_n^1(\cos \theta)}{\sin \theta}$$

$$\tau_n = \frac{d}{d\theta} (P_n^1(\cos \theta))$$

$\xi, \psi$ : Ricatti-Bessel functions

$P_n^1$ : 1<sup>st</sup> order Legendre Functions

# Critical Variables

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The equations are messy, but require just three inputs which are shown below.  
The nature of the inputs is important.

$$x = \pi D / \lambda$$

Decreasing wavelength is the same as increasing size. So, if you want to measure small particles, decrease wavelength so they “appear” bigger. That is, get a blue light source for small particles.

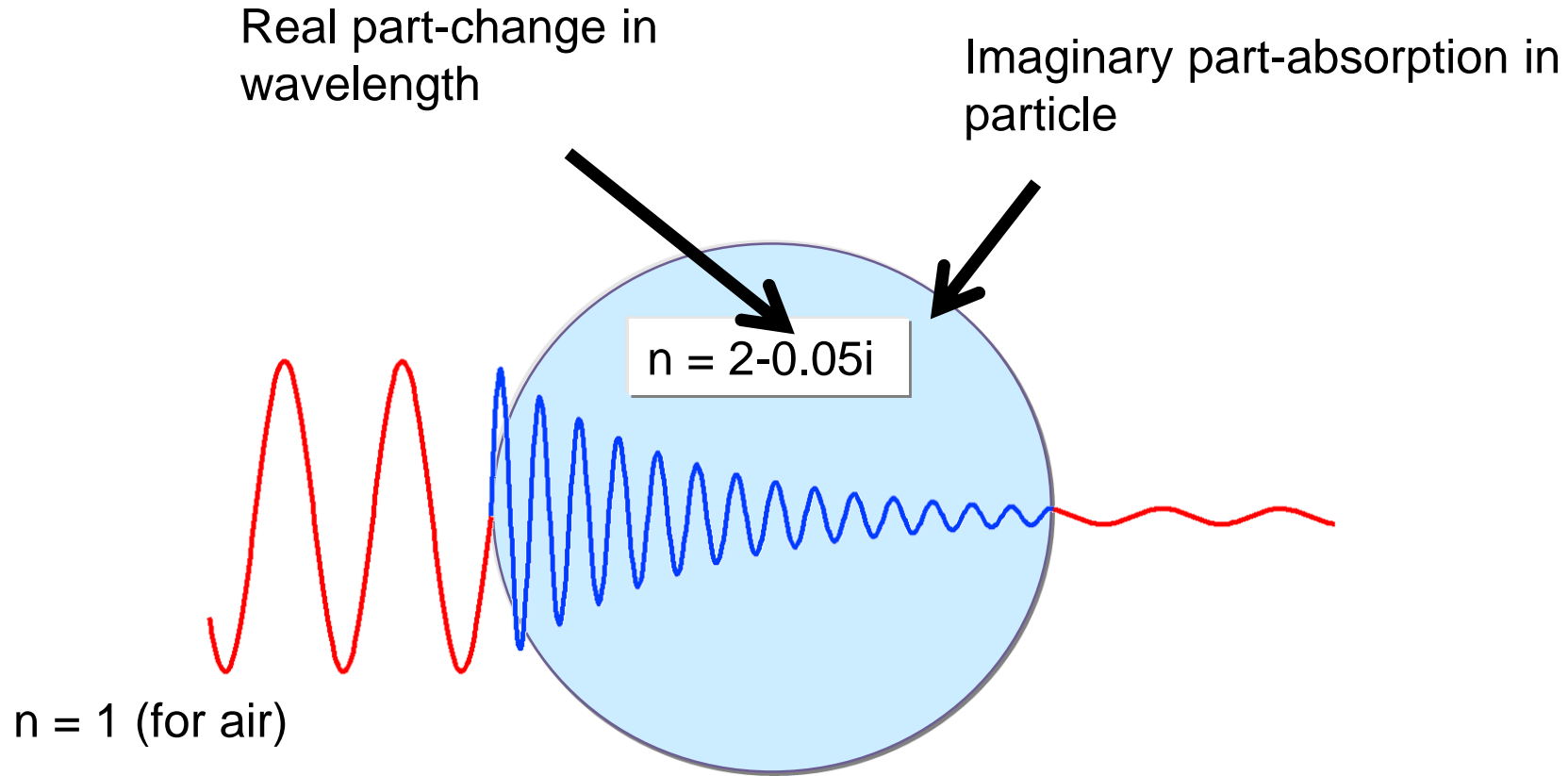
$$m = n_p / n_m$$

We need to know relative refractive index. As this goes to 1 there is no scattering.

$$\theta$$

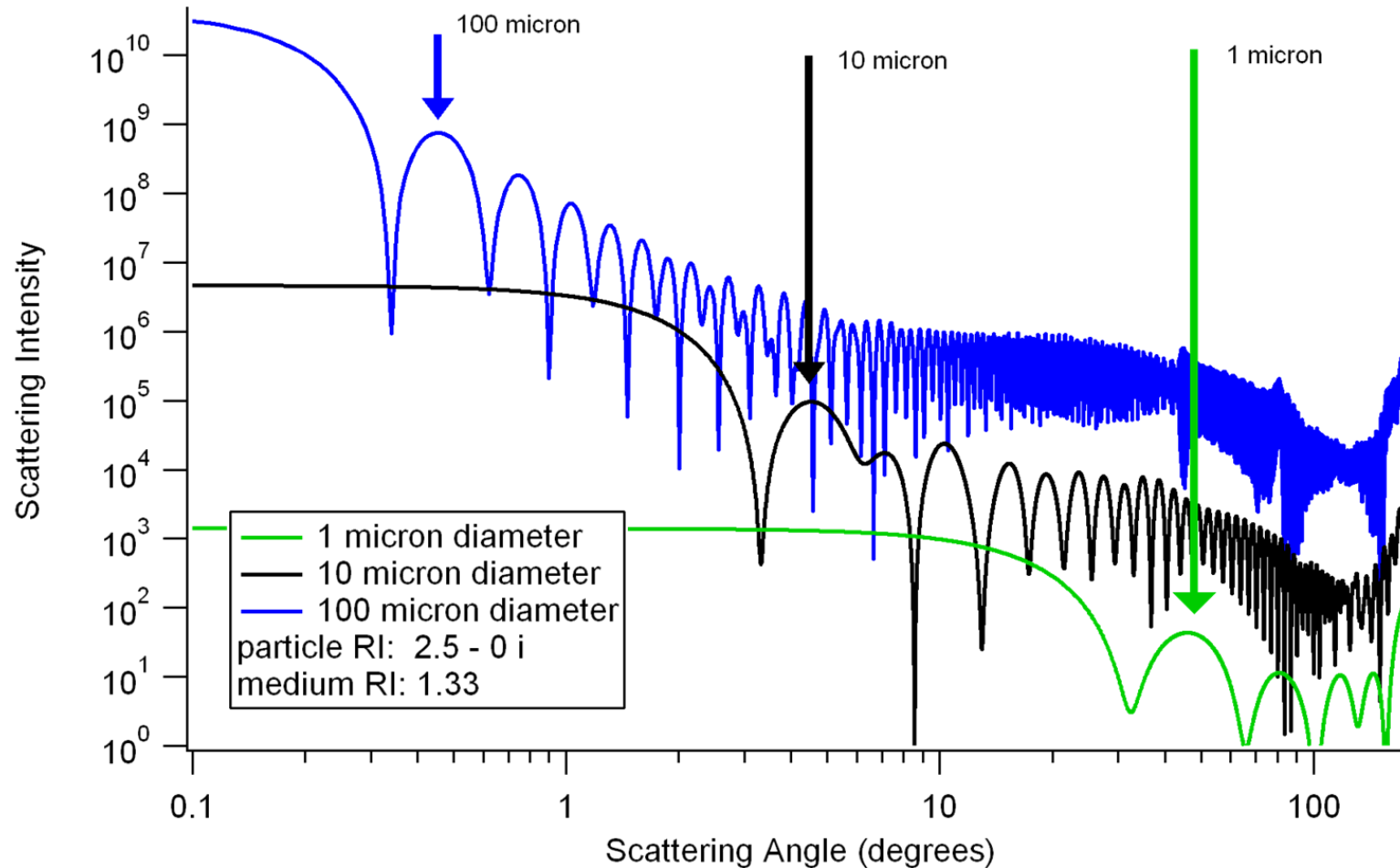
Scattering Angle

# Refractive Index



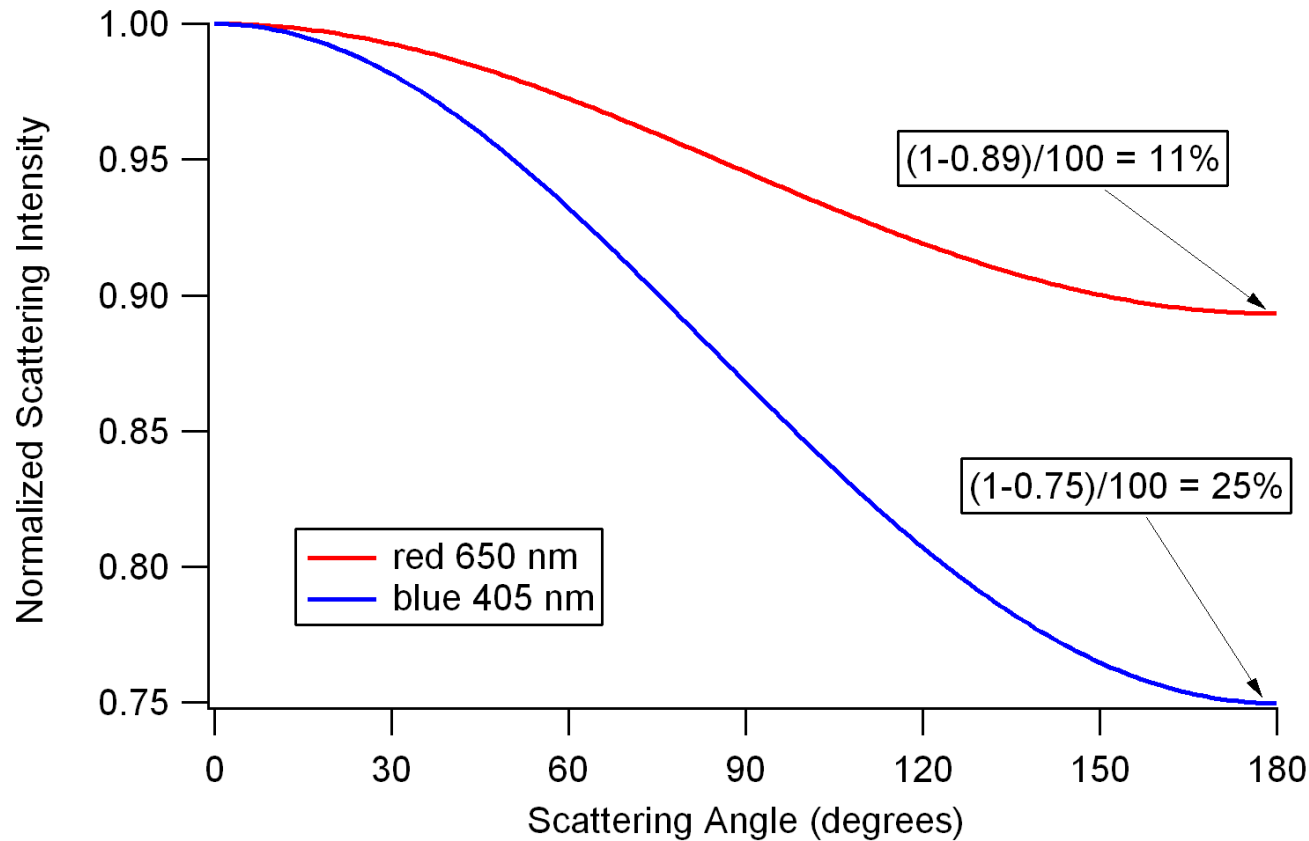
**ISO-13320:2020, 5.5.4:** “To obtain traceable results it is essential that the refractive index values are used as reported.”

# Effect of Size



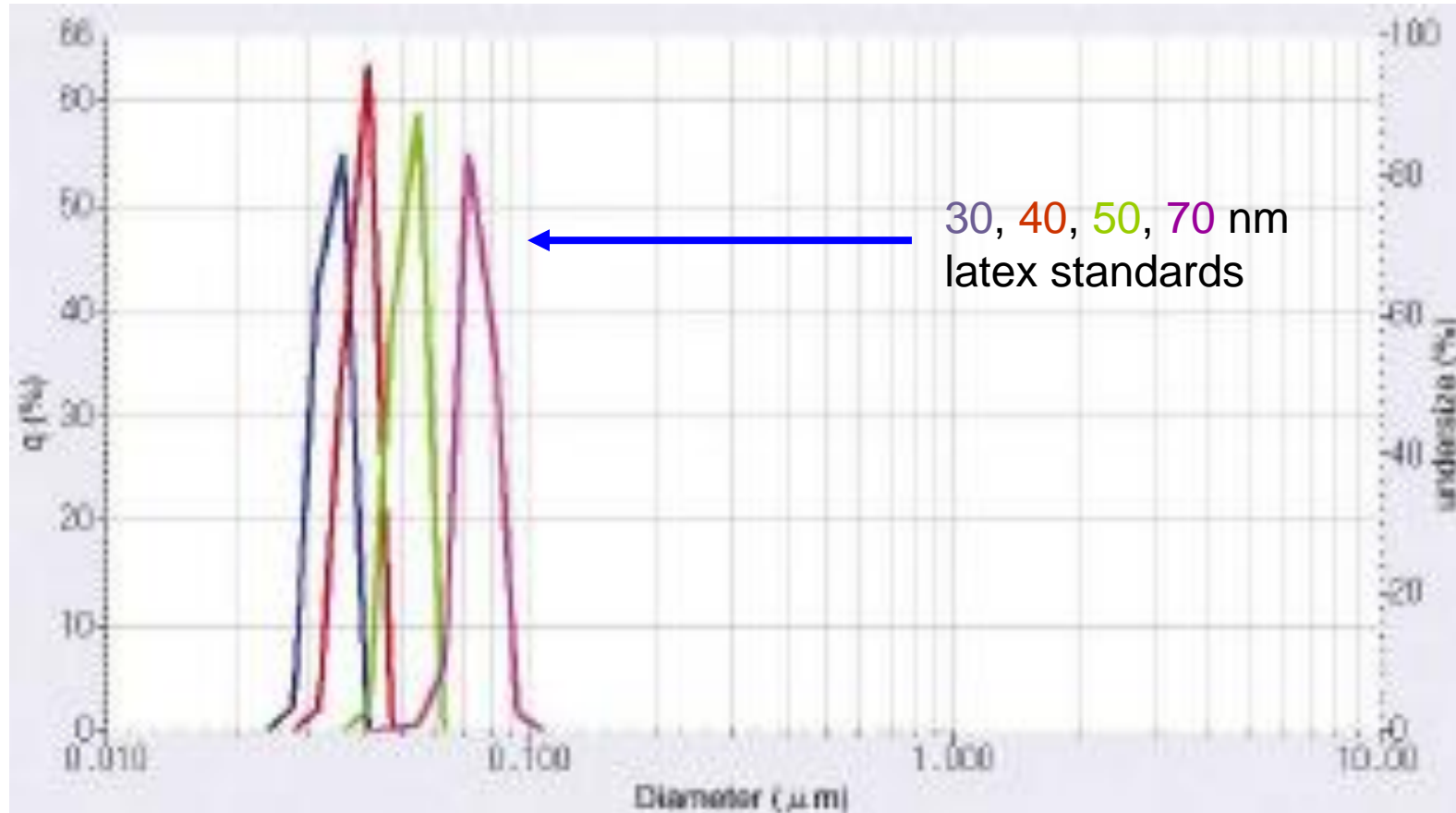
As diameter increases, intensity (per particle) increases and location of first peak shifts to smaller angle.

# Small Particles -> Blue light



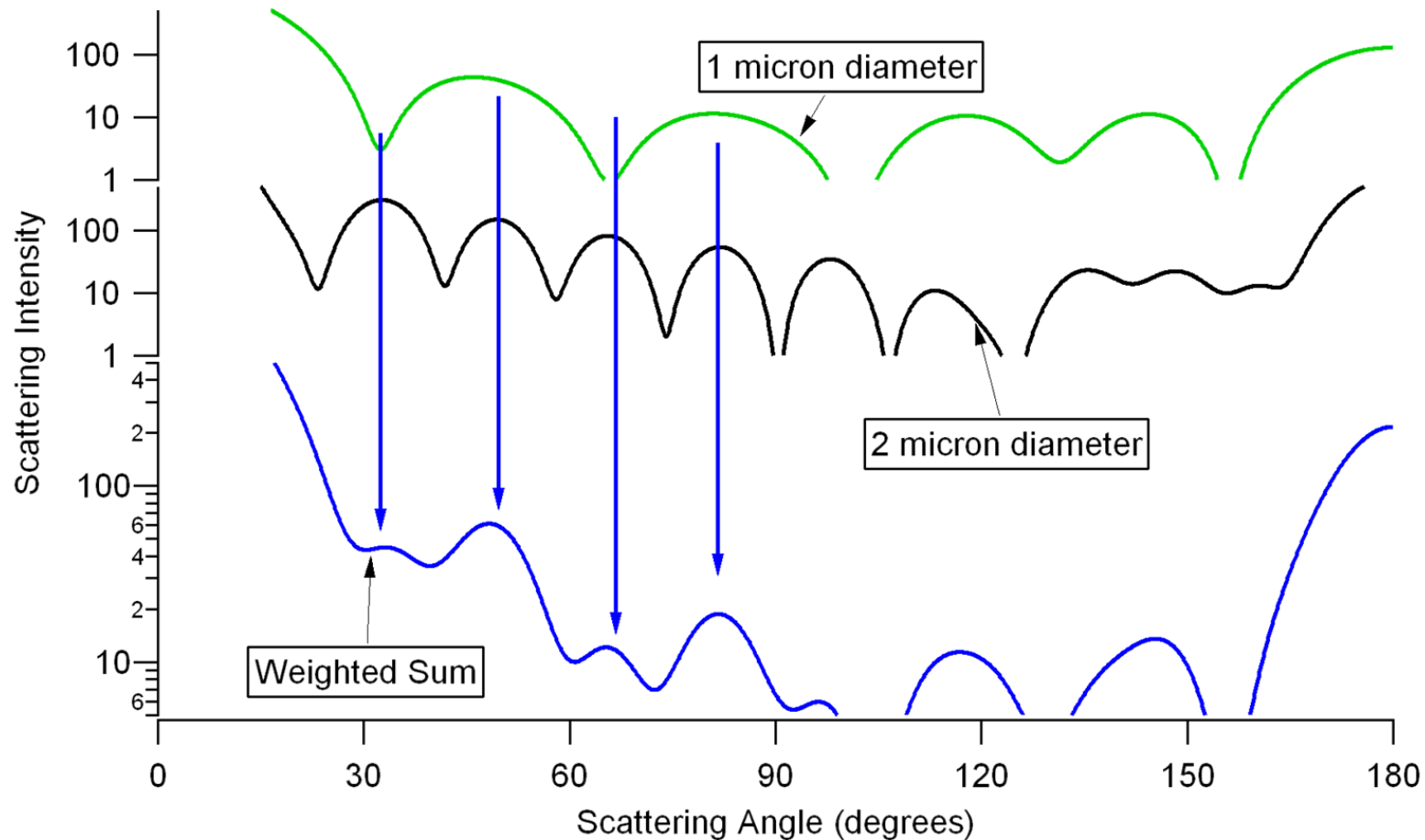
By using blue light source, we double the scattering effect of the particle. This leads to more sensitivity. This plot also tells you that you need to have the background stable to within 1% of the scattered signal to measure small particles accurately.

# Example Results



Data from very small particles.

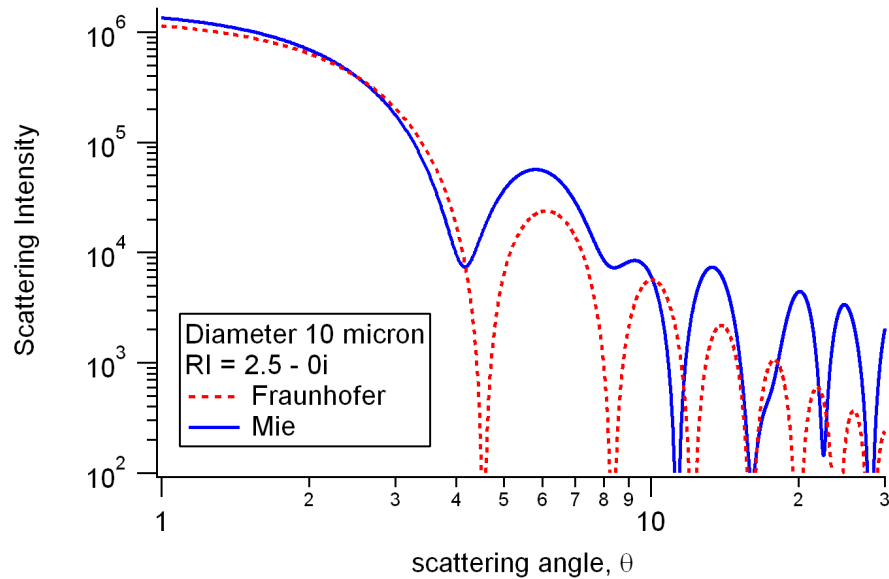
# Mixing Particles? Just Add



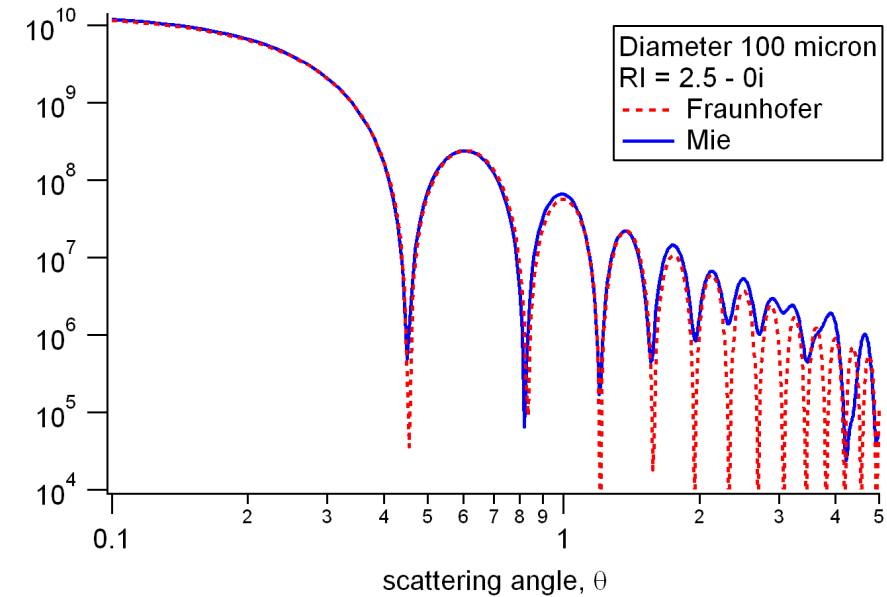
The result is the weighted sum of the scattering from each particle. Note how the first peak from the 2 micron particle is suppressed since it matches the valley in the 1 micron particle.



# Mie vs Fraunhofer



For small particles, match is poor. Use Mie.



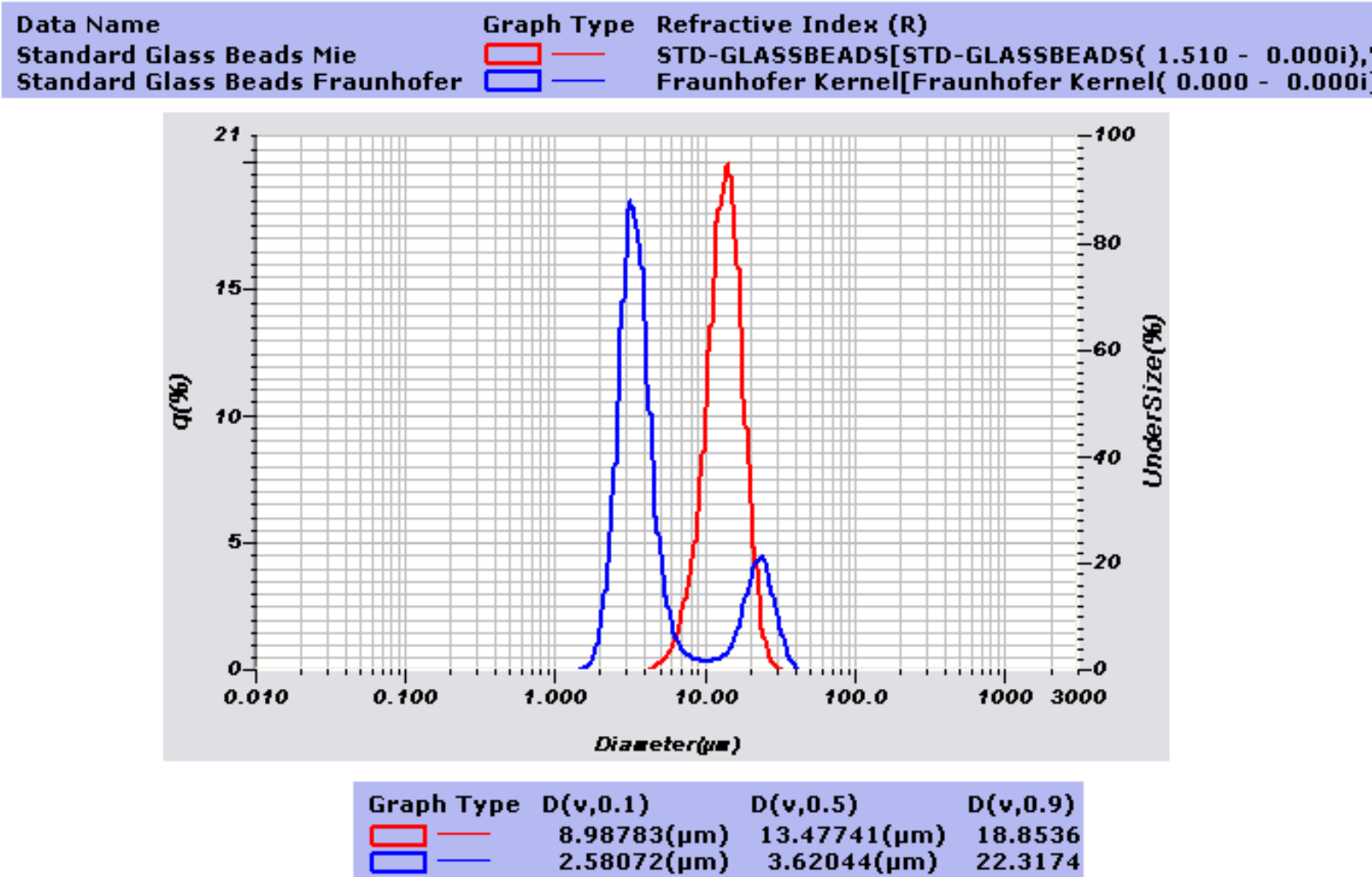
For large particles, match is good out to through several peaks.

## Computers are fast so no practical reason for Fraunhofer.



**ISO-13320:2020, A.5:**

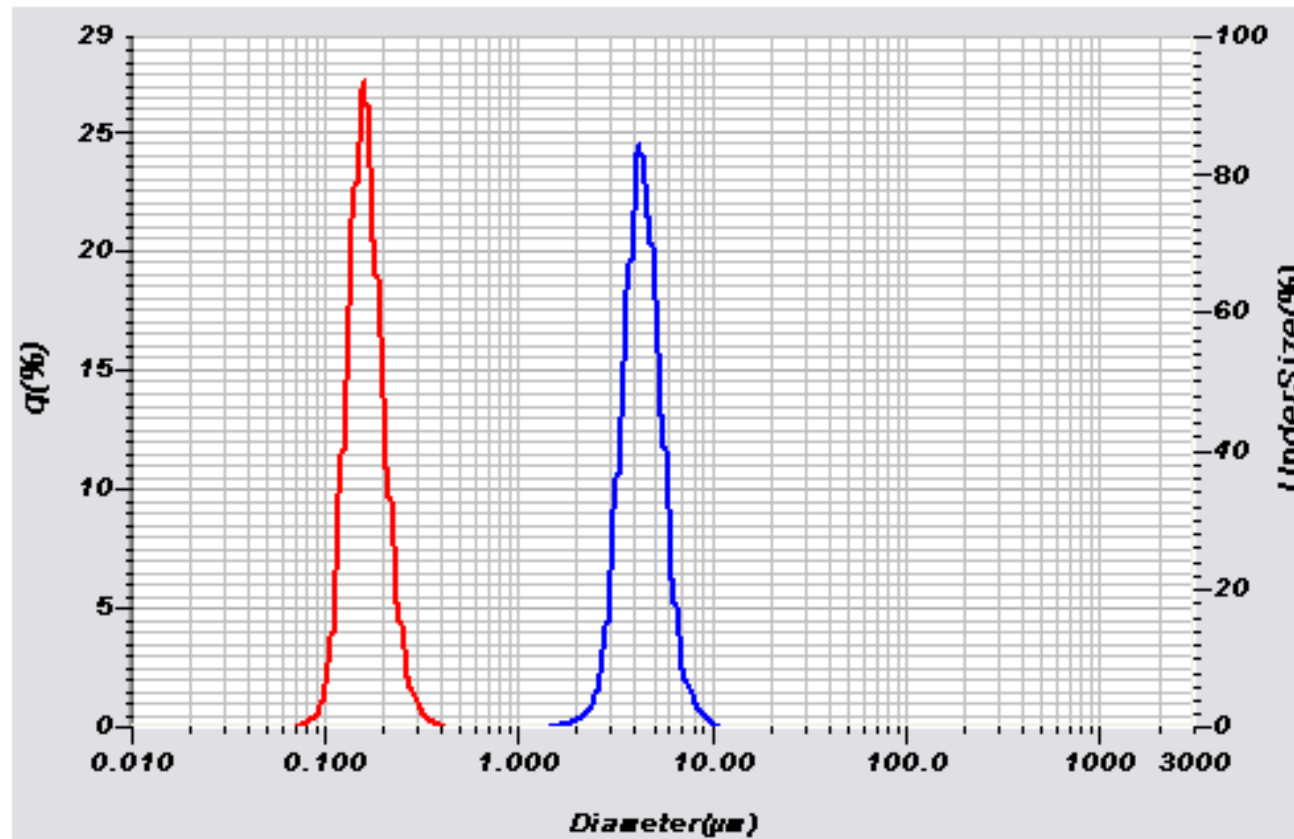
For most particles larger than about 50  $\mu\text{m}$  with relative refractive index greater than 1,2, such knowledge may not be necessary, as the Mie theory and Fraunhofer approximation give similar results.

# Glass Beads and Models



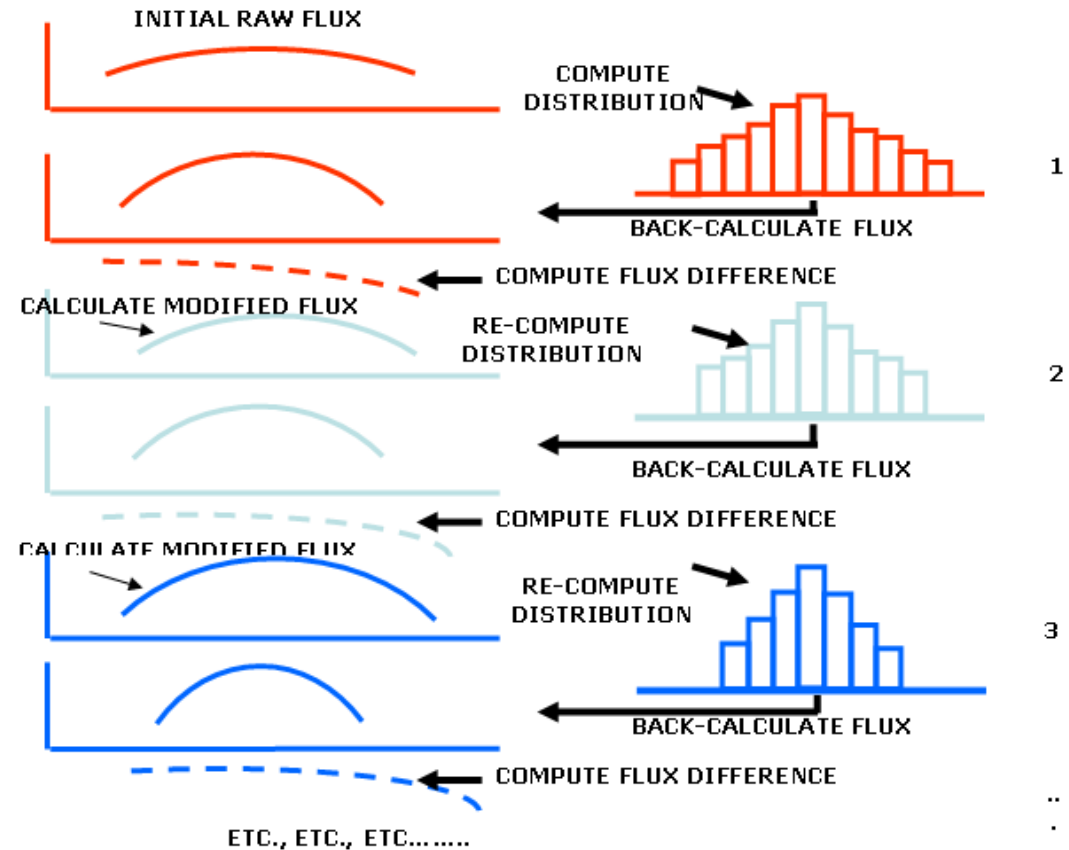
# CMP Slurry

| Data Name             | Graph Type   | Refractive Index (R)                                  |
|-----------------------|--|---|
| CMP Slurry Mie        |  — | 2.20-0.0i[2.20-0.0i( 2.200 - 0.000i),Water( 1.333)]   |
| CMP Slurry Fraunhofer |  — | Fraunhofer Kernel[Fraunhofer Kernel( 0.000 - 0.000i)] |



# Analyzing data: convergence

You (or the instrument manufacturer) will need to decide how to treat “borderline” data. Else noise will overly distort your results.



**ISO-13320:2020, A.9:**

Formulae such as [Formula \(A.8\)](#) are described as ill-posed and ill-conditioned. Even the smallest errors due to measurement make direct inversion without constraint unviable.

# Other factors

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**Size, Shape, and Optical Properties also affect the angle and intensity of scattered light**

**Extremely difficult to extract shape information without *a priori* knowledge**

**Assume spherical model**

# Pop Quiz

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**What particle shape is used for laser diffraction calculations?**

- A. Hard sphere
- B. Cube
- C. Pyramid
- D. Easy sphere

# Pop Quiz

---

**What particle shape is used for laser diffraction calculations?**

A. Hard sphere

B. Cube

C. Triangle

D. Easy sphere

Either gets full credit!





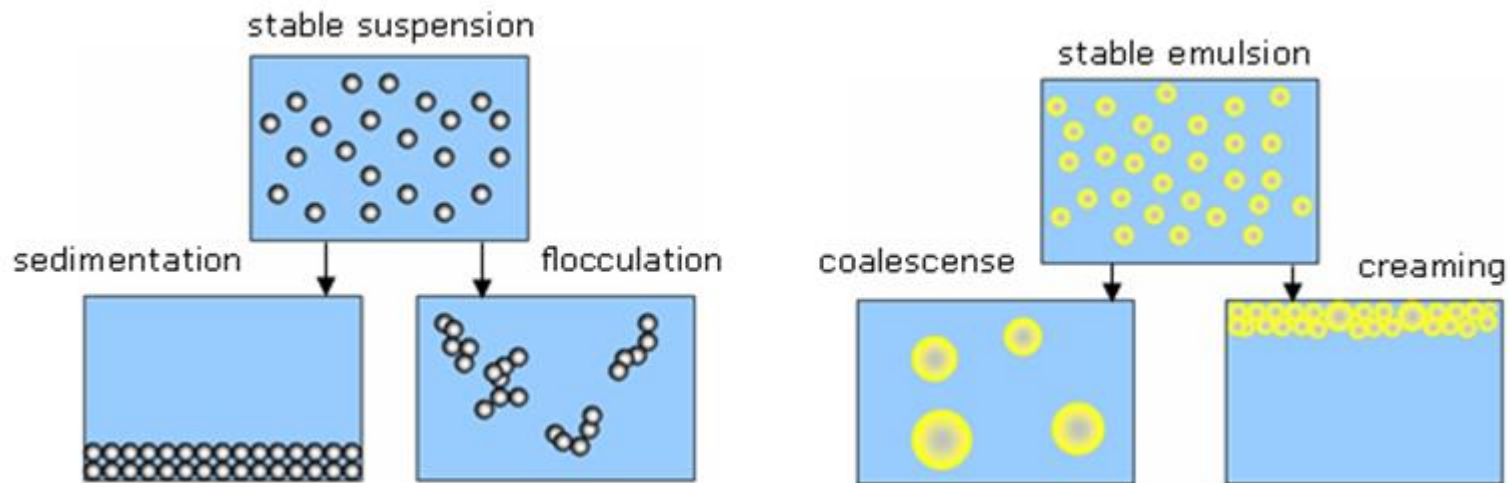
# Measurement Workflow

---

## Prepare the sample

Good sampling and dispersion a must!

May need to use surfactant or admixture



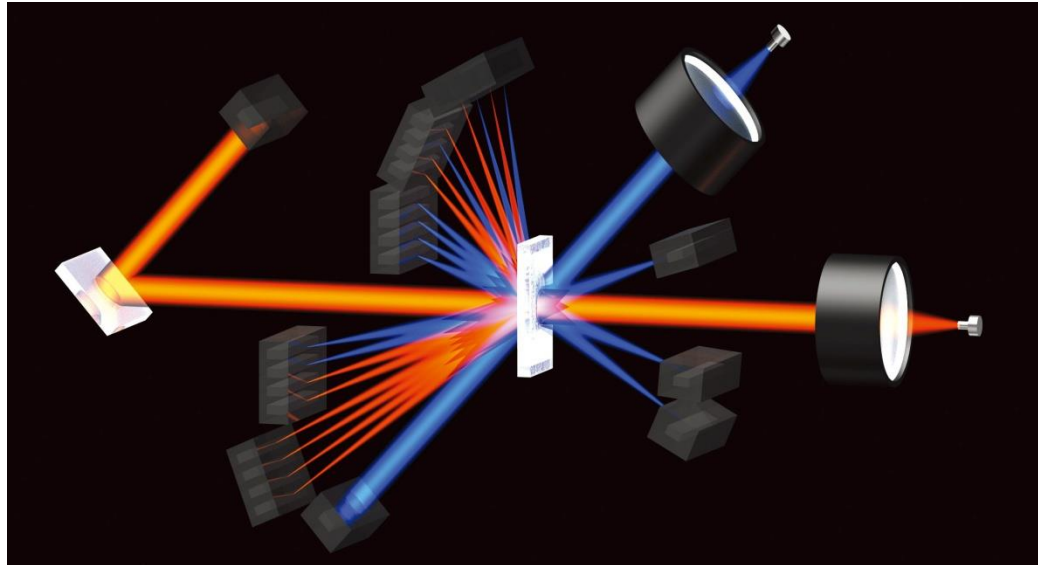
# Measurement Workflow

---

## Prepare the system

Align laser to maximize signal-to-noise

Acquire blank/background to reduce noise



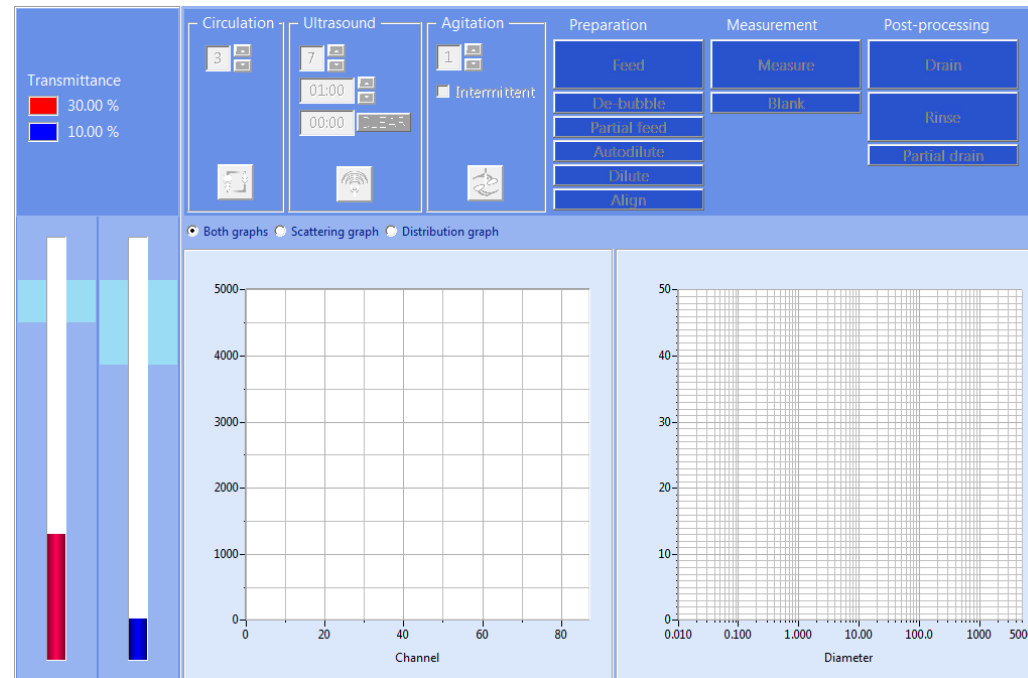
# Measurement Workflow

## Introduce sample

Add sample to specific concentration range

Pump sample through measurement zone

Final dispersion (ultrasonic)

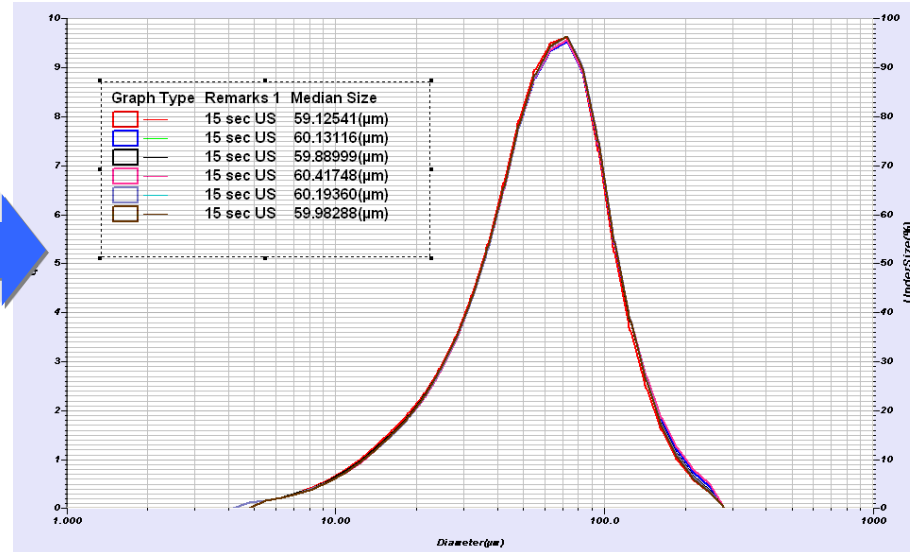
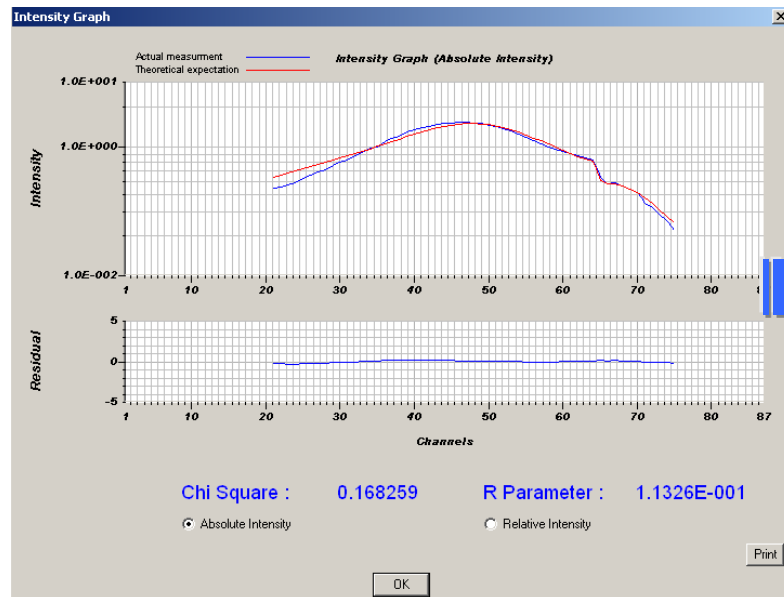


# Measurement Workflow

## Measurement

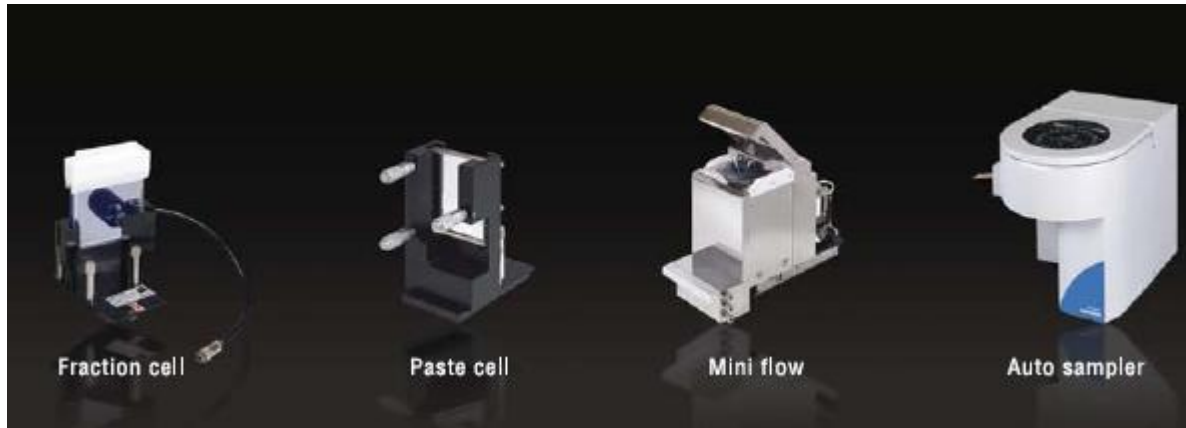
Click “Measure” button

- *Hardware* measures scattered light distribution
- *Software* then calculates size distribution



# Flexible Sample Handlers

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10 ml

35 ml

200 ml



powders

- Wide range of sample cells depending on application
- High sensitivity keeps sample requirements at minimum
- Technology has advanced to remove trade-offs

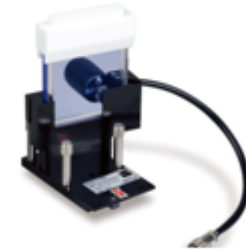
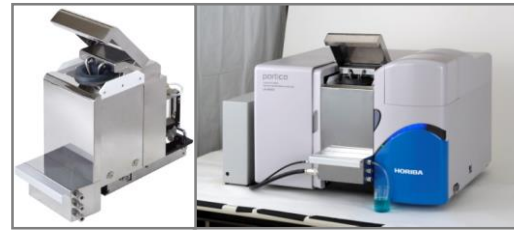
# How much sample (wet)?

It depends on sample, but here are some examples.

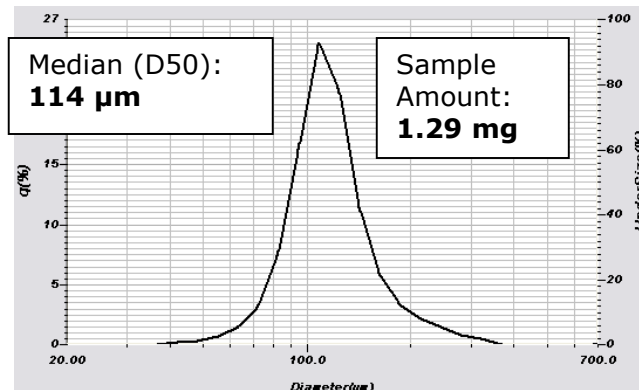
**Larger, broad distributions require larger sample volume**

**Lower volume samplers for precious materials or solvents**

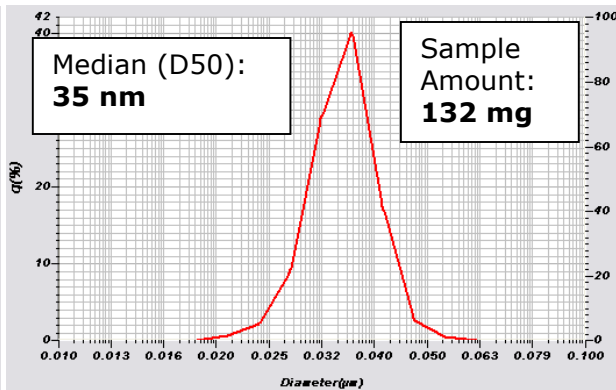
| Sample Handlers            | Dispersing Volume (mL) |
|----------------------------|------------------------|
| Aqua/Solvo Flow            | 180 - 330              |
| MiniFlow                   | 35 - 50                |
| Fraction Cell              | 15                     |
| Small Volume Fraction Cell | 10                     |



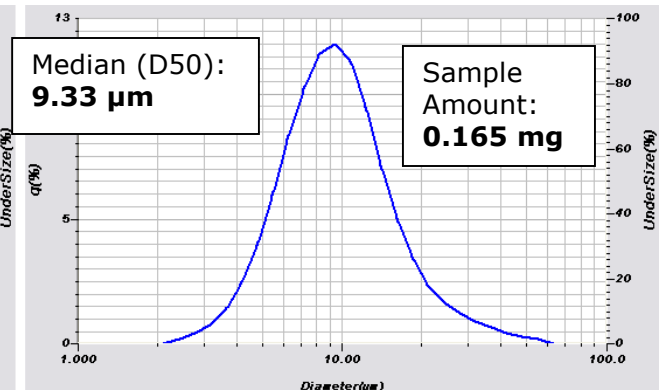
Note: Fraction cell has only magnetic stir bar, not for large or heavy particles



Bio polymer



Colloidal silica



Magnesium stearate

# Wet video

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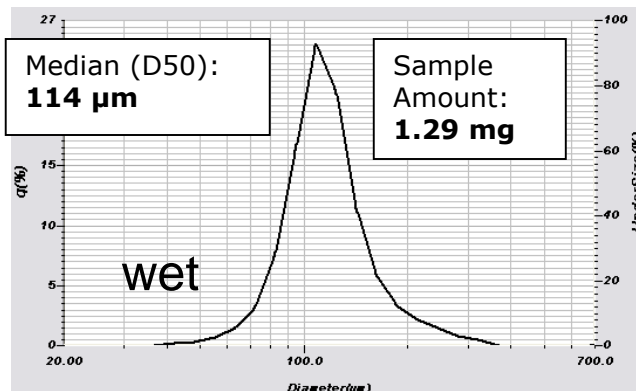


# How much sample (dry)?

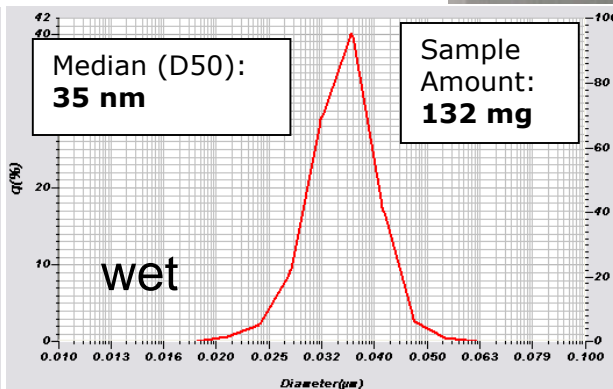
It depends on sample .....

**Larger, broad distributions require larger sample quantity**

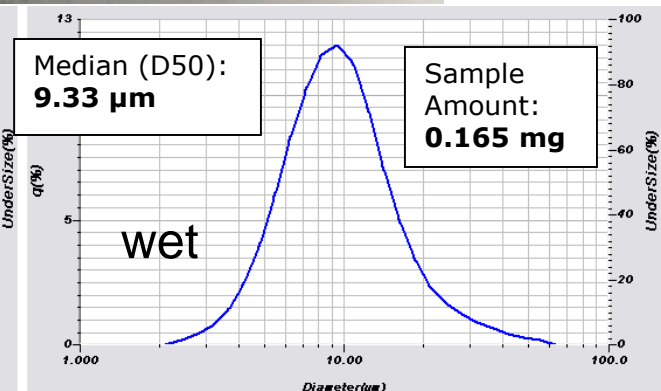
**Can measure less than 5 mg (over a number of particle sizes).**



Bio polymer



Colloidal silica



Magnesium stearate

# Dry video

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# Method Workflow

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**Determine particle refractive index (RI)**

**Choose diluent (water, surfactants, hexane, etc.)**

**Sampler selection: sample volume**

**Pump & stirrer settings**

**Concentration**

**Measurement duration**

**Does the sample need ultrasound?**

Document size-time plot

Disperse sample, but don't break particles

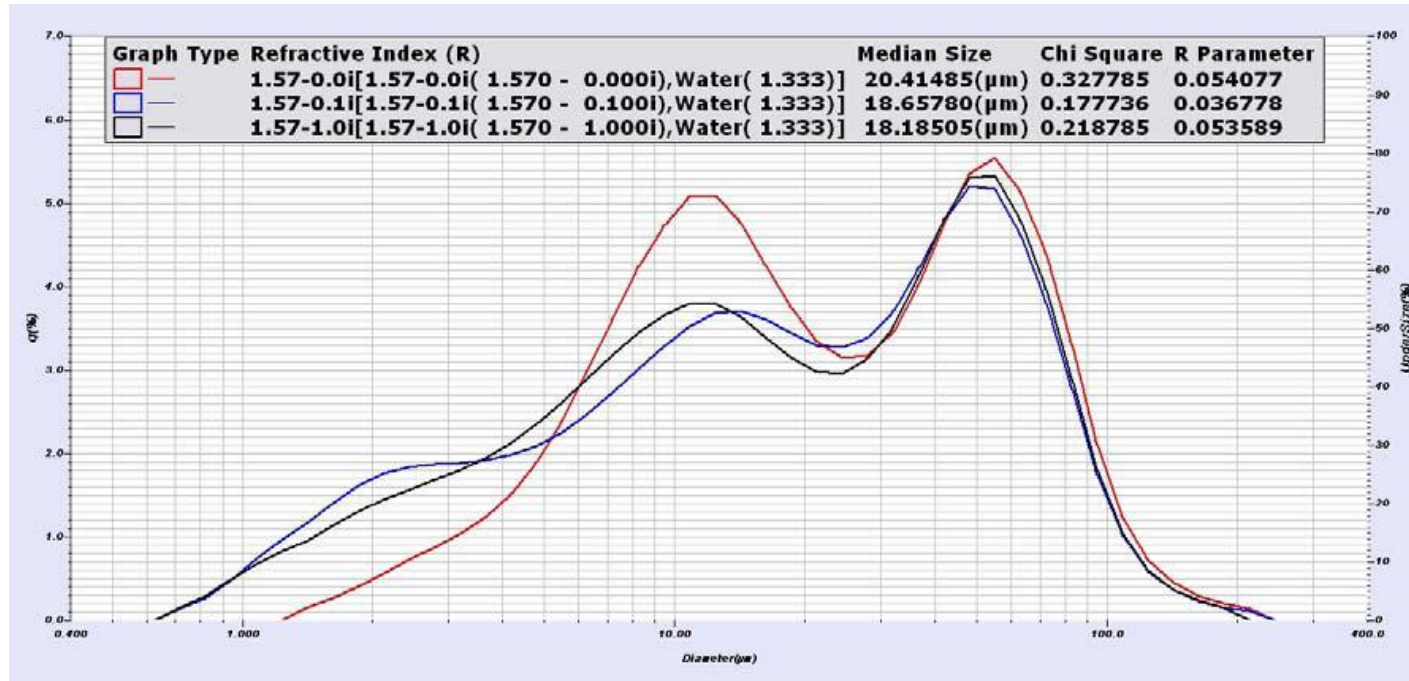
Check for reproducibility

# Determine Refractive Index

Real component via literature or web search, Becke line, etc.

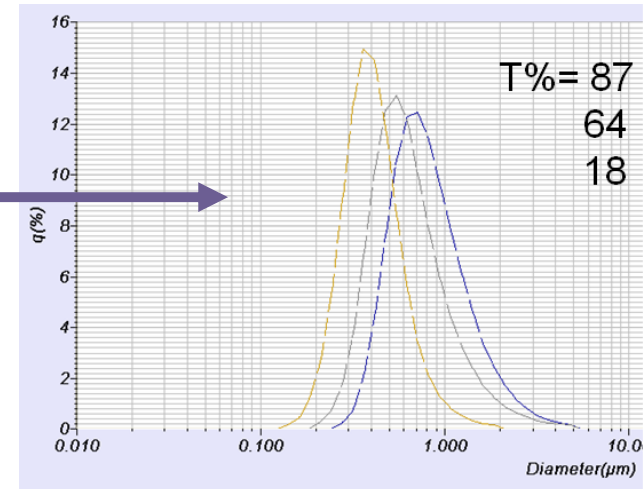
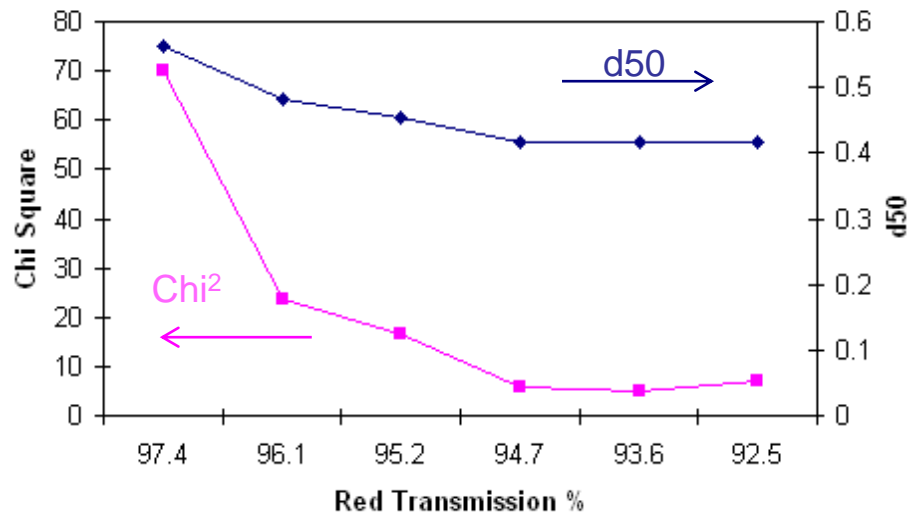
Measure sample, vary imaginary component to see if/how results change

Recalculate using different imaginary components, choose value that minimizes R parameter error calculation



# Concentration

High enough for good S/N ratio  
Low enough to avoid multiple scattering  
Typically 95 – 80 %T  
Measure at different T%, look at d50 result, Chi Square calculation



The screenshot shows the 'Method Expert Wizard' window, specifically the 'Particle Concentration Wizard' tab. It includes a 'Test Purpose' section with instructions on how to use the wizard. Below this, there are three steps: Step 1 (Choose either red or blue light for test), Step 2 (Select concentration test range), and Step 3 (Push 'Execute ...' button). The 'Execute Test Sequence >>' button is highlighted.

Method Expert Wizard

Circulation Pump Speed | Particle Concentration | Ultrasonic Treatment | Measurement Duration

### Measurement Optimization

#### Particle Concentration Wizard

Remember to click the button for more information.

**Test Purpose**

The purpose of this test is to discover a good concentration range of sample within the LA-950. Too little sample (i.e. too few particles) may not provide sufficient scattered light to escape the background. Too much sample may cause multiple scattering where light is scattered from many particles leading to poor accuracy.

[Test Design](#)

To evaluate the effect of concentration first choose the light source most appropriate for the sample (Step 1). Then we'll choose the Transmittance range within which we'll collect measurements every 5%T. (Step 2).

Step 1: Choose either red or blue light for test.

☒ Red ☐ Blue

(see Expert Advice for more information)

Step 2: Select concentration test range.

Max: 95(Default) Min: 60(Default)

Step 3: Push "Execute ..." button. This wizard is temporarily closed, and the test sequence is executed.

**Execute Test Sequence >>**

< Back Next >

# Ultrasonic Dispersion

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**Adding energy to break up agglomerates – disperse to primary particles, without breaking particles**

**Similar to changing air pressure on dry powder feeder**

**Typically set to 100% energy, vary time (sec) on**

**Investigate tails of distribution**

High end to see if agglomerates removed

Small end to see if new, smaller particles appear (breakage)

**Test reproducibility, consider robustness**

**Note:**

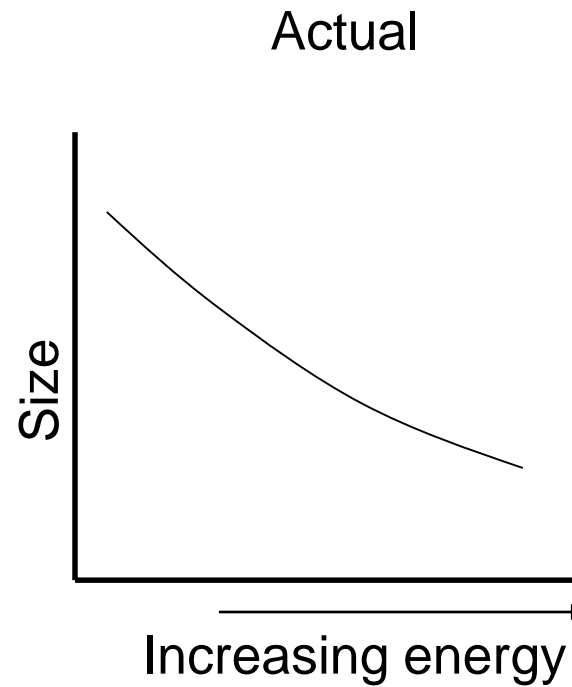
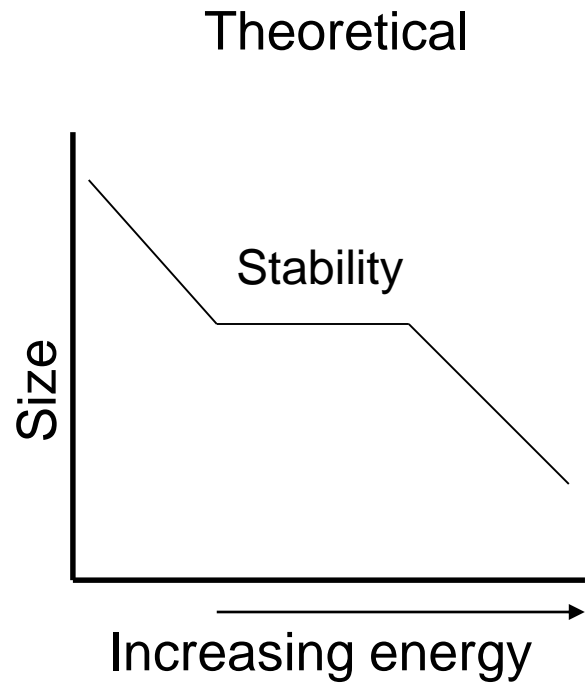
Do not use on emulsions

Can cause thermal mixing trouble w/solvents - wait

Use external probe if  $t > 2$ -5 minutes

# Dispersion vs. Breakage

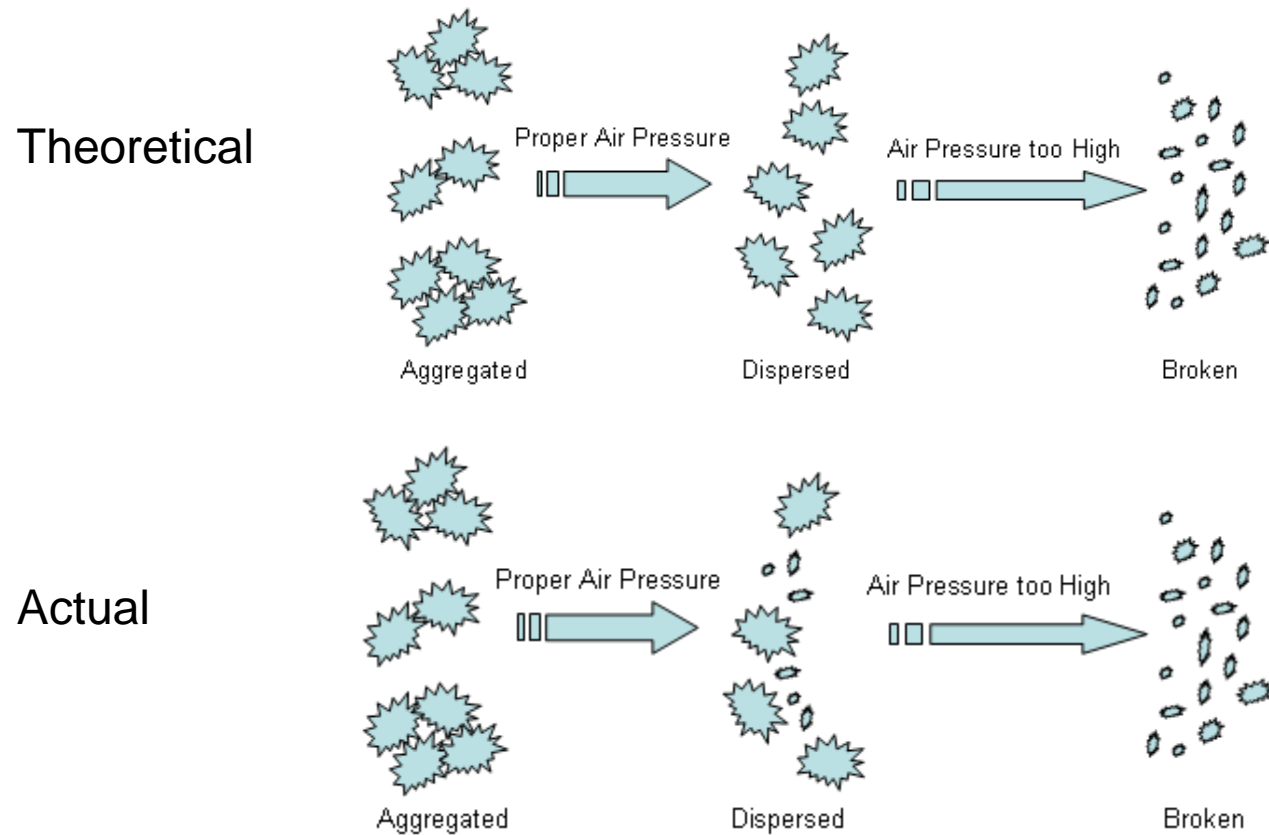
---



Higher air pressure or longer ultrasound duration

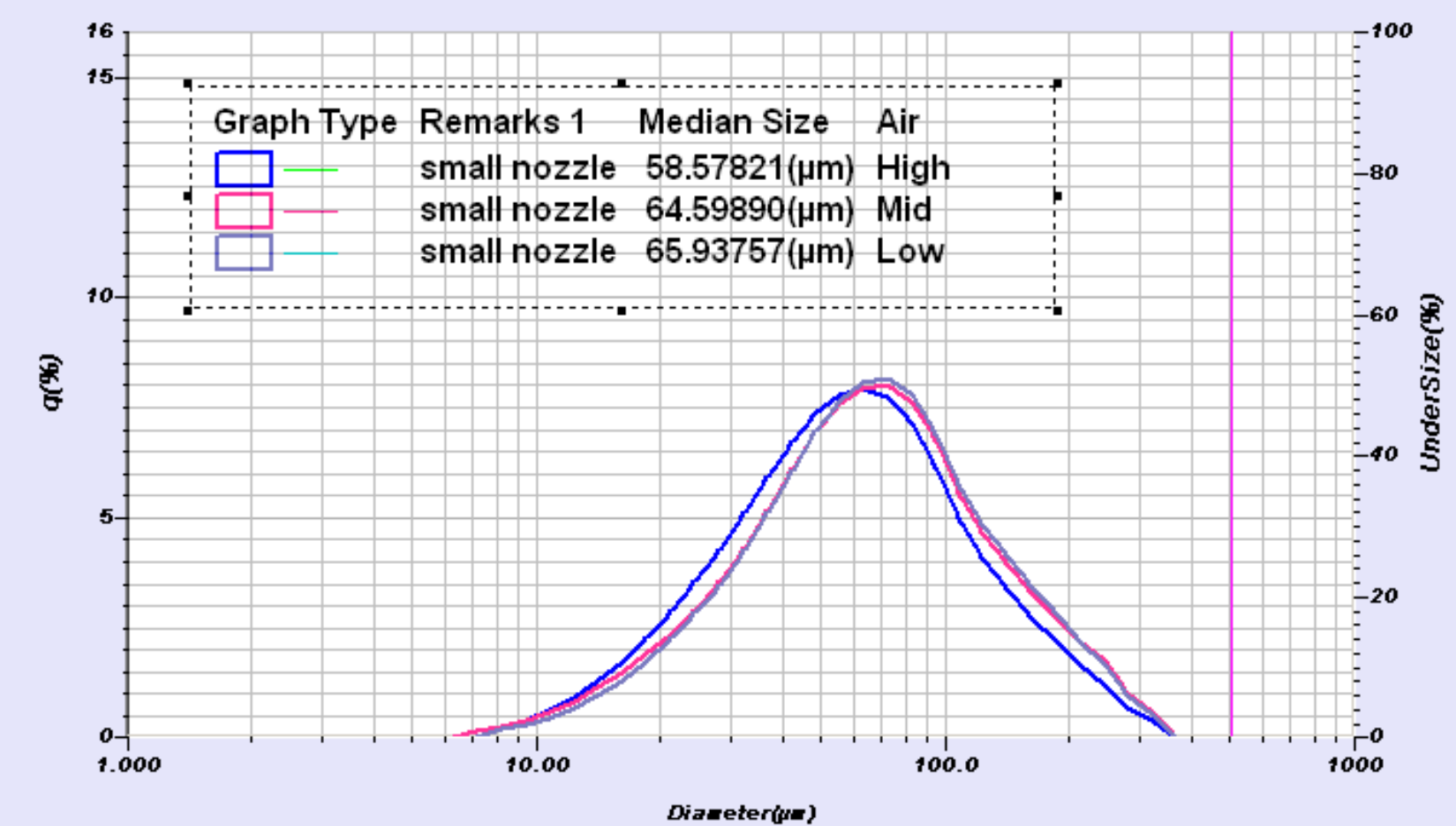
# Dispersion vs. Breakage

Dispersion and milling can be parallel rather than sequential processes





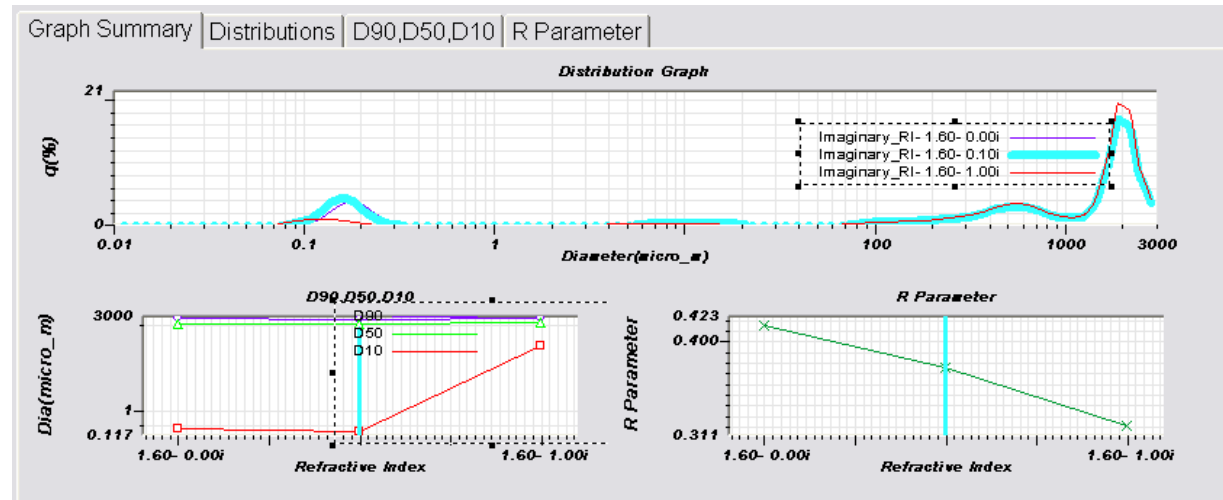
# Effect of Air Pressure: MCC



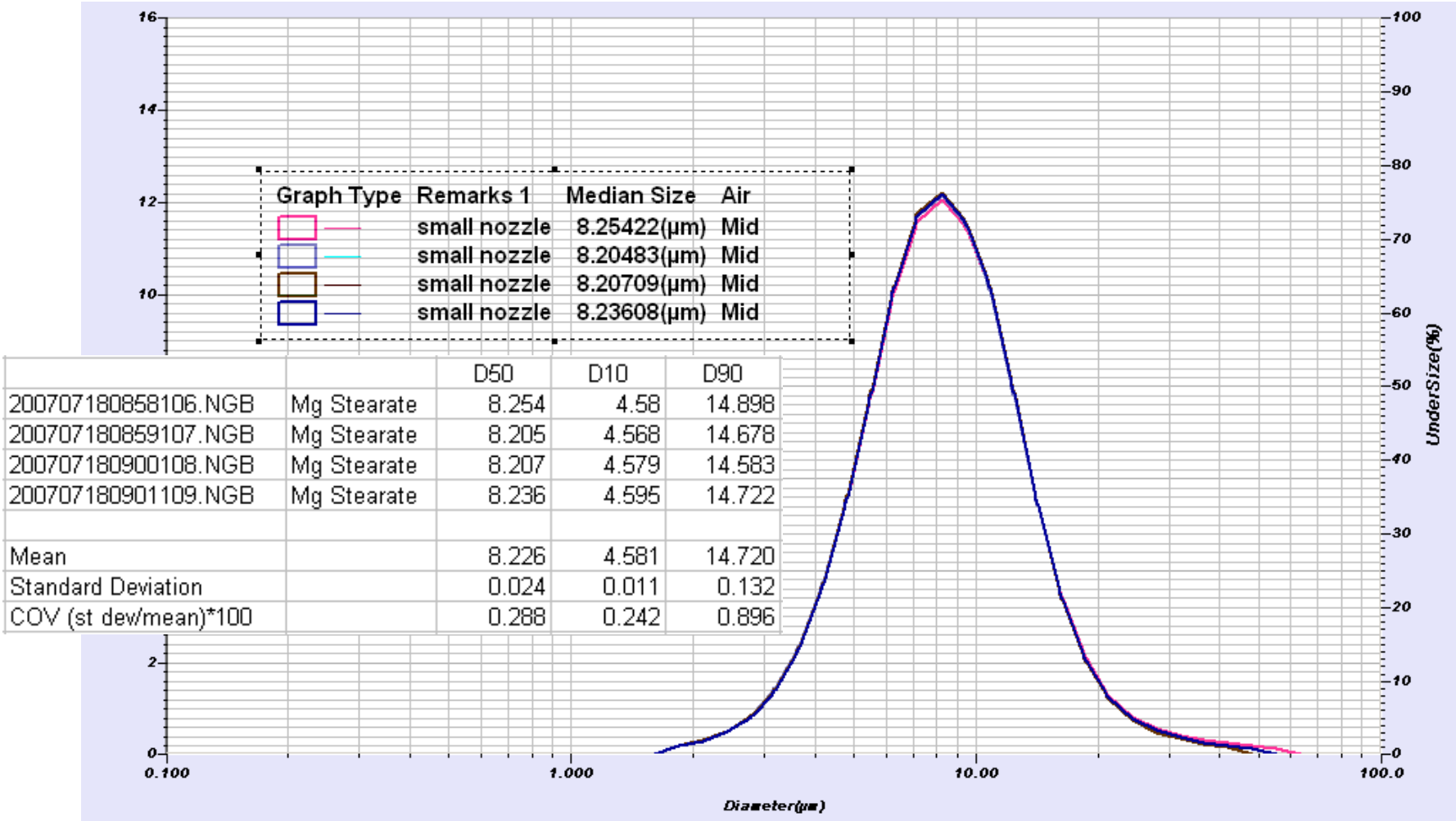
# LA-960 Method Expert

Method Expert guides user to prepare the LA-960 for each test

Results displayed in multiple formats:  
PSD, D50, R-parameter

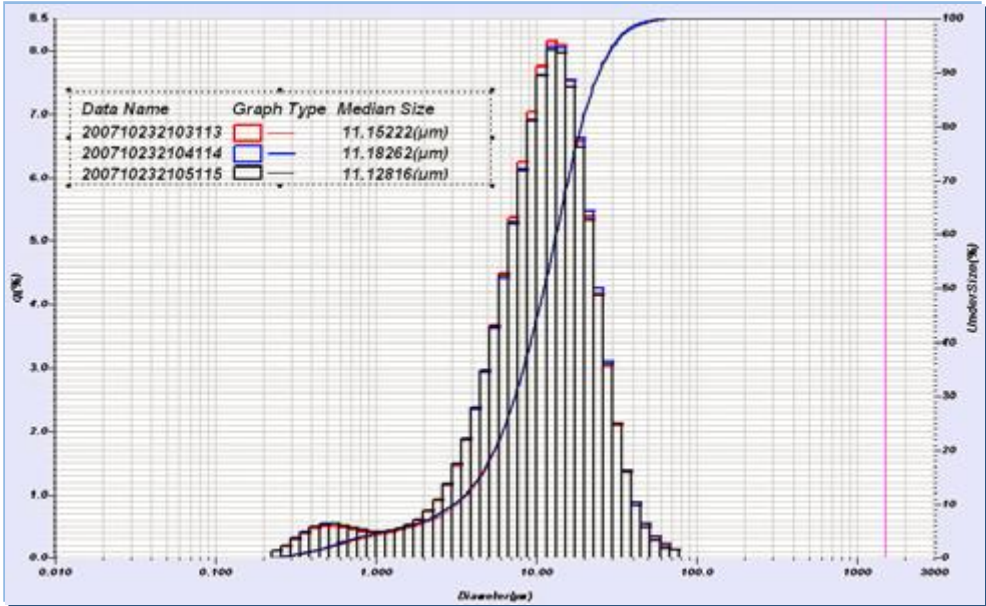


# Reproducibility– Mg Stearate dry, 2 bar



# Cement Dry

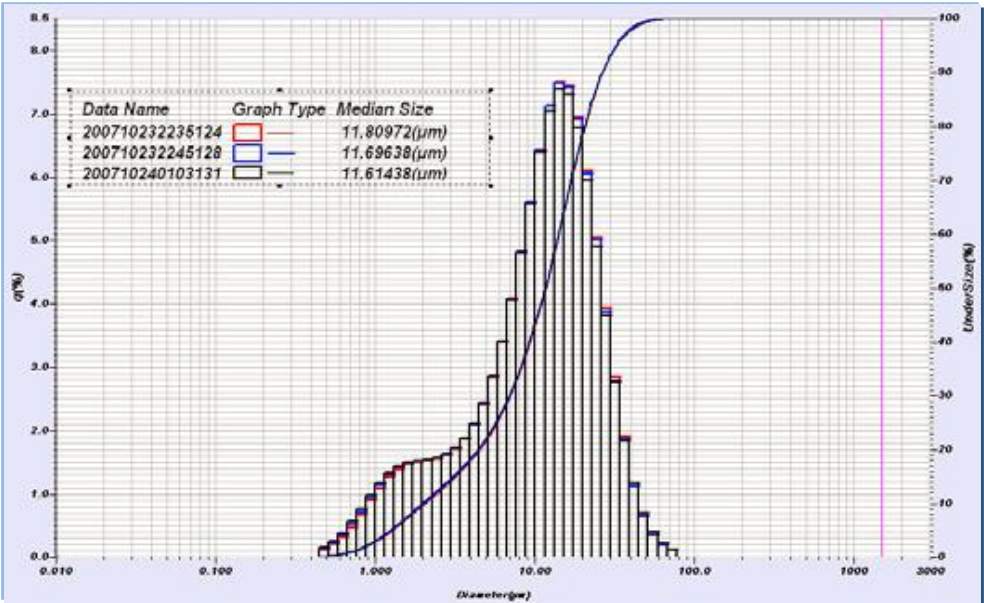
|                   | D10   | D50    | d90    |
|-------------------|-------|--------|--------|
| Portland Cement 1 | 3.255 | 11.152 | 24.586 |
| Portland Cement 2 | 3.116 | 11.183 | 24.671 |
| Portland Cement 3 | 3.112 | 11.128 | 24.92  |
| Average           | 3.161 | 11.154 | 24.726 |
| Std. Dev.         | 0.082 | 0.027  | 0.173  |
| CV (%)            | 2.6   | 0.24   | 0.70   |



# Cement Wet

Measure in isopropyl alcohol (IPA) (not water)

|                   | D10   | D50    | d90    |
|-------------------|-------|--------|--------|
| Portland Cement 1 | 2.122 | 11.81  | 27.047 |
| Portland Cement 2 | 2.058 | 11.696 | 26.743 |
| Portland Cement 3 | 1.999 | 11.614 | 27.001 |
| Average           | 2.06  | 11.707 | 26.93  |
| Std. Dev.         | 0.062 | 0.098  | 0.164  |
| CV (%)            | 3.0   | 0.84   | 0.61   |



# Instrument to instrument variation

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20 instruments, 5 standards

| Sample  | CV D10 | CV D50 | CV D90 |
|---|--------|--------|--------|
| PS202 (3-30μm)  | 2%     | 1%     | 2%     |
| PS213 (10-100μm)  | 2%     | 2%     | 2%     |
| PS225 (50-350μm)  | 1%     | 1%     | 1%     |
| PS235 (150-650μm)   | 1%     | 1%     | 2%     |
| PS240 (500-2000μm)  | 3%     | 2%     | 2%     |
| These are results from running polydisperse standards on 20 different instruments |        |        |        |

# Instrument to instrument variation

## Industrial Samples

|                | Dmean | D5  | D10 | D50 | D90 | D95 |
|----------------|-------|-----|-----|-----|-----|-----|
| Average (nm)   | 155   | 112 | 119 | 152 | 193 | 208 |
| Std. Dev. (nm) | 0.8   | 0.8 | 0.7 | 1.0 | 1.1 | 0.7 |
| CV (%)         | 0.5   | 0.7 | 0.6 | 0.6 | 0.6 | 0.3 |

e 8: Instrument to instrument variation across four LA-950 systems for Formulation 1.

|               | Dmean | D5  | D10 | D50 | D90 | D95 |
|---------------|-------|-----|-----|-----|-----|-----|
| Average (nm)  | 193   | 136 | 147 | 187 | 247 | 264 |
| Std. Dev (nm) | 1.5   | 0.5 | 0.4 | 0.6 | 0.4 | 1.1 |
| CV (%)        | 0.8   | 0.4 | 0.3 | 0.3 | 0.2 | 0.4 |

e 9: Instrument to instrument variation across four LA-950 systems for Formulation 2.

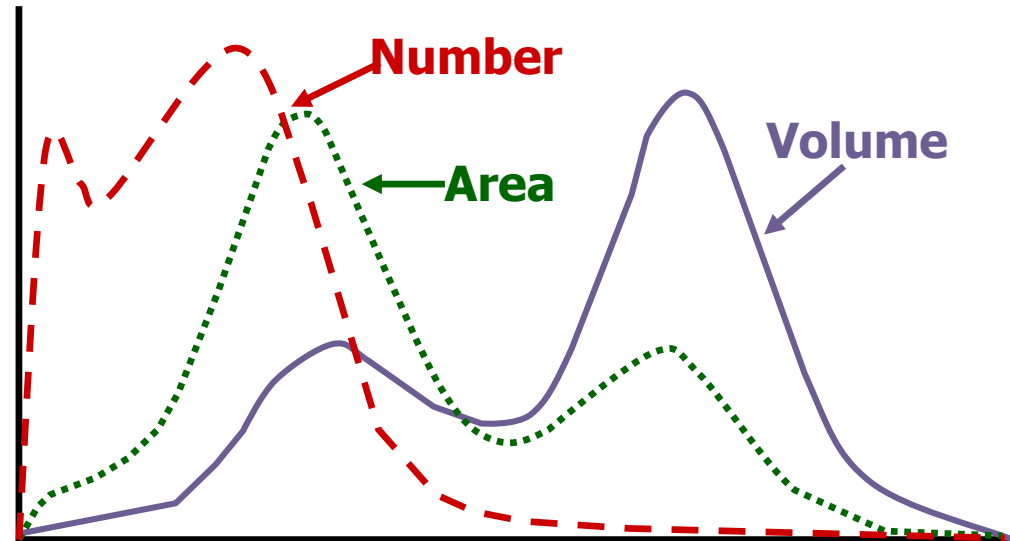
# Diffraction Drawbacks

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## Volume basis by default

Although excellent for mass balancing, cannot calculate number basis without significant error

## No shape information





# Benefits

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## **Wide size range**

Most advanced analyzer measures from 10 *nano* to 5 *milli*

## **Flexible sample handlers**

Powders, suspensions, emulsions, pastes, creams

## **Very fast**

Allows for high throughput, 100's of samples/day

## **Easy to use**

Many instruments are highly automated with self-guided software

## **Good design = Excellent precision**

Reduces unnecessary investigation/downtime

## **First principle measurement**

No calibration necessary

## **Massive global install base/history**

Omoshiro-okashiku  
Joy and Fun

おもしろおかしく

THANK YOU

Terima kasih  
谢谢  
Gracias  
Σας ευχαριστώ πάρα πολύ  
धन्यवाद  
شُكْرًا  
Danke  
Tack ska du ha  
Grazie  
ขอบคุณครับ  
Большое спасибо  
Cảm ơn  
감사합니다  
Dziękuję  
Obrigado  
Merci  
ありがとうございました

# Hegman Gauge

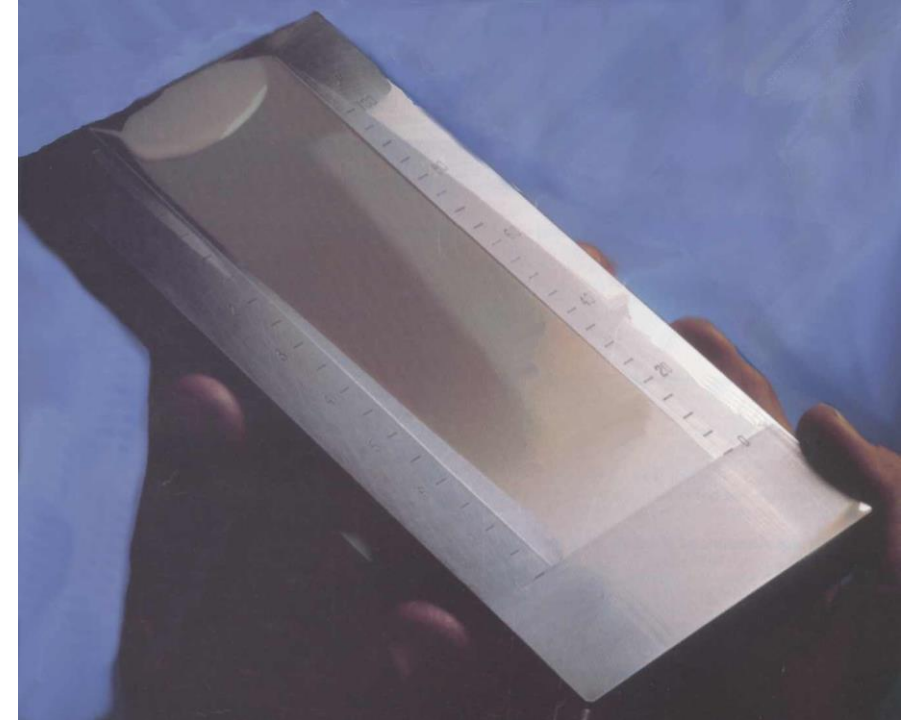
## Used in paint and coatings industry

Device has tapered center channel

Slurry is placed in channel, then straight edge is drawn across it

“Hegman Number” is where particles disturb smooth surface of slurry

**Information from largest particles only – no distribution**



More info at:

<https://www.horiba.com/int/products/scientific/particle-characterization/particle-analysis-webinar-series/particle-classroom-series-i-introduction-to-particle-analysis/>